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UNITED STATES OF AMERICA  
FEDERAL TRADE COMMISSION

In the Matter of: )  
Rambus, Inc. ) Docket No. 9302  
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Monday, July 21, 2003  
9:30 a.m.

TRIAL VOLUME 46  
PART 1  
PUBLIC RECORD

BEFORE THE HONORABLE STEPHEN J. McGUIRE  
Chief Administrative Law Judge  
Federal Trade Commission  
600 Pennsylvania Avenue, N.W.  
Washington, D.C.

Reported by: Susanne Bergling, RMR

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## P R O C E E D I N G S

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JUDGE McGUIRE: This hearing is now in order.

4

Counsel, how is everyone doing this morning?

5

Before we get started, are there any items we

6

need to take up?

7

MR. PERRY: Yes, Your Honor. We wanted to let

8

you know that we will complete our case next Tuesday

9

afternoon, the 29th.

10

JUDGE McGUIRE: Okay.

1           MR. PERRY: And Your Honor, there may well be  
2 issues with respect to what they want to do in the  
3 rebuttal case as to whether it's fair rebuttal.

4           JUDGE McGUIRE: Right. I suggest you two, each  
5 side confer in the interim on that, and at whatever  
6 time that we might engage in that, how much time does  
7 complaint counsel anticipate it's going to take to put  
8 on their rebuttal case?

9           MR. OLIVER: Again, I'm not certain at this  
10 point, Your Honor, but I think it would be less than a  
11 week.

12          JUDGE McGUIRE: It would be less than a week,  
13 okay.

14          MR. OLIVER: Your Honor, could I have one  
15 moment to consult with counsel here?

16          JUDGE McGUIRE: Yes, go ahead.

17          (Counsel conferring.)

18          MR. OLIVER: Your Honor, we also received  
19 notice today that Mr. Teece is going to be their  
20 witness for Thursday and Friday. I just wanted to  
21 mention for Your Honor's information that Mr. Royall  
22 was scheduled to handle Mr. Rapp as well as Mr. Teece,  
23 and Mr. Royall unfortunately has been ill and was in  
24 the hospital yesterday, and I believe that he was  
25 planning to try to nevertheless go forward with Mr.

1 Rapp tomorrow, but in light of his condition, I frankly  
2 don't know at this point whether he would be in a  
3 position to continue with Mr. Teece later this week. I  
4 will speak with him this morning or at the lunch break.

5 JUDGE MCGUIRE: Yeah, I will hold that in  
6 abeyance, and I guess -- when you say sometime next  
7 week, do you mean sometime before their case in chief  
8 being --

9 MR. OLIVER: No, I simply said because of Mr.  
10 Royall's illness and the fact that he was in the  
11 hospital yesterday and the fact that I don't know  
12 exactly what his condition is today, that we are hoping  
13 he would be in condition to go forward with Mr. Rapp  
14 tomorrow.

15 JUDGE MCGUIRE: Okay, I got you.

16 MR. OLIVER: But at this point, we don't know  
17 whether he will be able to go forward with Mr. Teece  
18 Thursday and Friday.

19 MR. PERRY: I'm not quite sure what Mr. Oliver  
20 is suggesting, whether there would be somebody else to  
21 examine the witness or whether we should stop our case  
22 at this point, and I don't know that we should do the  
23 latter. I know that people have travel plans.

24 JUDGE MCGUIRE: Well, I am not going to stop  
25 the case on that.

1           Do you want to respond to that further, Mr.  
2 Oliver? Are you saying if he is not out of the  
3 hospital by the time they put on this witness, I guess  
4 you should follow up and give us a little more input on  
5 what your alternative would be if he's unable to  
6 conduct that cross examination.

7           MR. OLIVER: Well, he is out of the hospital,  
8 Your Honor, but I do want to consult with Mr. Royall as  
9 well as with the other side to see what arrangement we  
10 might be able to make.

11           JUDGE MCGUIRE: And you will do that, what,  
12 today?

13           MR. OLIVER: Yes.

14           JUDGE MCGUIRE: All right, very good.

15           All right, if there are no other items to come  
16 before the Court at this time, the respondent may call  
17 its next witness.

18           MR. DETRE: Thank you, Your Honor. Respondent  
19 calls Michael Geilhufe.

20           JUDGE MCGUIRE: Sir, would you please approach  
21 the Bench and be sworn in by the court reporter.  
22 Whereupon--

23                                   MICHAEL GEILHUFÉ  
24 a witness, called for examination, having been first  
25 duly sworn, was examined and testified as follows:



1 JUDGE McGUIRE: Have a seat right there, Mr.  
2 Geilhufe.

3 THE WITNESS: Thank you, Your Honor.

4 DIRECT EXAMINATION

5 BY MR. DETRE:

6 Q. Good morning, Mr. Geilhufe.

7 A. Good morning.

8 Q. Could you please state your full name for the  
9 record?

10 A. Michael Geilhufe.

11 Q. And how do you spell that last name?

12 A. G E I L H U F E.

13 Q. And where do you live, Mr. Geilhufe?

14 A. I live in Palo Alto, California.

15 Q. How long have you lived there?

16 A. I've lived in Palo Alto for seven years; in the  
17 Bay Area for 35 years.

18 Q. Are you presently employed?

19 A. I am formally retired. I am very active in  
20 private business matters.

21 Q. What sort of private business matters are you  
22 involved in?

23 A. I'm a serial entrepreneur. I'm an investor in  
24 a number of young startup companies. I am involved in  
25 funding or identifying funding for young startup

1 companies. I am on the board of a semiconductor memory  
2 company. And I'm on the board of advisers for two  
3 other companies.

4 Q. Prior to this matter, have you ever been an  
5 expert witness before?

6 A. No, I have not.

7 Q. If we could step back a little bit, could you  
8 give a brief summary of your educational background,  
9 starting with your undergraduate degree?

10 A. My Bachelor's Degree in electrical engineering  
11 is from the University of California at Berkeley.

12 Q. What year is that?

13 A. And that was in the year 1965, a long time ago.  
14 And my major was computer science and semiconductor  
15 devices.

16 Q. And did you get any further degrees after that?

17 A. Yes, I then received a Master's in electrical  
18 engineering and semiconductor devices from California  
19 State University at Long Beach in 1967.

20 Q. And did you get any further degrees after that?

21 A. Yes, I received a Master's of business  
22 administration from the University of Santa Clara,  
23 specializing in entrepreneurship.

24 Q. Do you recall what year that was?

25 A. That was in 1971.

1 Q. When did you get your first full-time job?

2 A. In 1965.

3 Q. Where did you work?

4 A. I worked for Collins Radio in Newport Beach,  
5 California.

6 Q. And what did you do there?

7 A. I was a research engineer in the  
8 microelectronics research operation for Collins Radio.

9 Q. And how long were you at Collins?

10 A. I was there for two years.

11 Q. What did you do after that?

12 A. After that, I joined Lockheed Missile and Space  
13 Company in Sunnyvale, California.

14 Q. And what did you do at Lockheed?

15 A. I worked as a microelectronics research  
16 engineer at Lockheed. I worked on some parts for the  
17 Poseidon Missile, and I did the first integrated  
18 circuit at Lockheed.

19 Q. And after -- how long were you at Lockheed?

20 A. Approximately two years.

21 Q. What did you do after that?

22 A. After that, I joined a startup company called  
23 Advanced Memory Systems in Sunnyvale, California. I  
24 was responsible for memory product design.

25 Q. And how long were you at Advanced Memory

1 Systems?

2 A. I was at Advanced Memory Systems approximately  
3 four years.

4 Q. So, during what period of time was that?

5 A. Approximately 1968 to '72.

6 Q. And could you give a little bit more detail  
7 about what sort of projects you were involved in at  
8 Advanced Memory Systems?

9 A. Yes, Advanced Memory Systems was founded as a  
10 semiconductor memory company. It was founded at the  
11 same time as Intel, the two companies that had  
12 attempted to build semiconductor memories. That  
13 technology did not exist before 1968.

14 Q. And what specific projects were you involved in  
15 at Advanced Memory Systems?

16 A. I designed the first commercial DRAM, a  
17 P-channel DRAM. I then designed a number of other  
18 products that were successful in the marketplace, DRAM  
19 products.

20 Q. Okay. And what did you do after you left  
21 Advanced Memory Systems?

22 A. I was recruited to Intel in 1972, early '73, to  
23 take over the memory development responsibility for  
24 Intel Corporation.

25 Q. And during what period of time were you

1 employed at Intel?

2 A. I was employed -- I was formally employed  
3 between 1973 to 1988. There was a one-year sabbatical  
4 in there.

5 Q. When you first started with Intel in 1973, what  
6 were your job responsibilities?

7 A. I was -- I was responsible for developing all  
8 semiconductor memory products at Intel, specifically  
9 the 4K DRAM at that time.

10 In addition to that, I was responsible for  
11 developing DRAM products -- excuse me, SRAM products,  
12 bipolar memory products, peripheral products and -- and  
13 two years later, nonvolatile memory products.

14 Q. And at some point did your job responsibilities  
15 at Intel change?

16 A. Yes.

17 Q. When was that?

18 A. I was moved to a corporate responsibility in  
19 the 1978 time frame, I believe, corporate  
20 responsibility for reliability engineering.

21 JUDGE MCGUIRE: Now, let me just inject. I'm  
22 hearing what you did, but I haven't heard your titles  
23 in these various jobs, sir, if you might just throw  
24 that in for the record so I'll know what titles you had  
25 during this period.

1 THE WITNESS: All right, sir, okay.

2 BY MR. DETRE:

3 Q. During that first period of time at Intel when  
4 you were designing DRAM and memory products, what was  
5 your title then?

6 A. My title was memory development manager, and at  
7 Intel, that was the senior development position at that  
8 time.

9 Q. Okay, then I believe you testified that at some  
10 point you became responsible for reliability at Intel,  
11 and what was your title at that point?

12 A. That title was director of reliability  
13 engineering.

14 Q. And could you give a little bit of further  
15 detail about what your responsibilities entailed in  
16 that position?

17 A. Yes, as -- I was responsible for the design  
18 reliability, process reliability and manufacturing  
19 reliability of all Intel products at all factories of  
20 Intel.

21 Q. And what sort of products did that involve?

22 A. That, of course, included DRAMs, SRAMs, EPROMs,  
23 microcontrollers, microprocessors, peripheral chips,  
24 literally the entire product suite.

25 Q. And then at some time did you assume another

1 position at Intel?

2 A. Yes, I then assumed the position of director of  
3 quality -- worldwide quality assurance, and that added  
4 to the reliability responsibility the quality assurance  
5 responsibility.

6 Q. When were you in that position?

7 A. I was in that position in 1980 and '81.

8 Q. Okay. And did your responsibilities -- how did  
9 your responsibilities change when you assumed that  
10 position?

11 A. The staff size grew significantly. At that  
12 point I had a 600-person staff around the world, and  
13 several manufacturing plants were added to my  
14 responsibility.

15 Q. And what did you do at Intel after 1981?

16 A. I went on sabbatical. I went on a sailing  
17 trip.

18 Q. How long did your sabbatical last?

19 A. Approximately 11 months.

20 Q. And did you then return to Intel?

21 A. That is correct.

22 Q. And what was your position when you returned to  
23 Intel?

24 A. I returned to Intel as director of systems  
25 quality and reliability.

1 Q. And were your responsibilities in that position  
2 different from your prior responsibilities at Intel?

3 A. Exactly. My prior responsibilities were  
4 components-related responsibilities. The systems  
5 responsibilities related to motherboards, memory  
6 systems, development systems, systems similar to  
7 today's PCs.

8 Q. Okay. Did those systems involve DRAMs?

9 A. Of course.

10 Q. How long were you in that position?

11 A. Approximately two years.

12 Q. And what did you -- what position did you  
13 assume after that?

14 A. I was then -- I moved to the position of  
15 general manager and director of components contracting.

16 Q. And during what years were you in that  
17 position?

18 A. Approximately '84 to '87-'88.

19 Q. And what were your -- what were your  
20 responsibilities in that position?

21 A. My responsibility was to establish, negotiate  
22 and manage international manufacturing operations for  
23 Intel; that is, manufacturing operations under contract  
24 in Japan, in Korea, in the United States and in Taiwan.

25 Q. What sort of products were being manufactured



1 for Intel under contract?

2 A. Generally the low cost products,  
3 microcontrollers of memory -- EPROMs and DRAMs.

4 Q. And could you give some idea of what sort of  
5 companies you were interacting with during this period?

6 A. Yes. In Japan, I worked closely with  
7 Mitsubishi, with Sanyo, with OKI -- these are all the  
8 semiconductor divisions of those very large  
9 companies -- Rohm. In Korea, I worked very closely  
10 with Samsung, and in Taiwan, I worked very closely with  
11 TSIC.

12 Q. And did you then assume some further position  
13 at Intel after that?

14 A. I also handled business development activities  
15 towards the end of that particular tenure. One of the  
16 businesses I established was a DRAM distribution  
17 business.

18 Q. Okay. And what had -- and erther yDRAM disl 8Fmen  
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1 A. Yes, I did.

2 Q. For how long?

3 A. I worked at Information Storage Devices through  
4 1998.

5 Q. What sort of technology was Information Storage  
6 Devices developing?

7 A. The company developed a unique multi-level  
8 storage technology that is a technology where one  
9 memory cell can store more than one bit of information,  
10 in our case eight bits.

11 Q. Did any of your work at Information Storage  
12 Devices involve DRAMs?

13 A. It -- DRAM involvement was -- well, let me back  
14 up.

15 Information Storage Devices was a fabless  
16 semiconductor company. As such, we contracted with  
17 companies to manufacture our products. Our products  
18 were being fabricated in one case in a DRAM fab.

19 Q. And you became familiar with that DRAM fab?

20 A. Intimately familiar.

21 Q. What did you do after your tenure at  
22 Information Storage Devices?

23 A. Information Storage Devices as a public company  
24 was sold to Winbond Electronics, a Taiwanese company,  
25 and I continued as a vice president for that company,

1 vice president of -- and general manager of the  
2 operation for that company for a year and a half.

3 Q. I'm sorry, what was that company?

4 A. Winbond, W I N B O N D.

5 Q. And what sort of business was Winbond in?

6 A. Winbond is in the consumer electronics  
7 component business. The largest part of its business  
8 is DRAMs.

9 Q. And what did you do after Winbond?

10 A. After Winbond, I began investing in young  
11 startup companies. Specifically, I invested in  
12 Advanced Radio Sales, and shortly after I invested, I  
13 was asked to become chairman of the company, executive  
14 chairman of the company, and I operated in that mode  
15 until the company was merged about a month ago.

16 Q. Okay. Now, over the course of your career,  
17 have you --

18 JUDGE MCGUIRE: Be we get started, I want to  
19 clarify something. You had introduced him when you  
20 called him as doctor, but I don't believe you went  
21 into --

22 THE REPORTER: No, that was my error.

23 JUDGE MCGUIRE: I was going to say, you didn't  
24 inquire about his Ph.D. or anything.

25 MR. DETRE: No, I am not aware that Mr.

1 Geilhufe has a Ph.D.

1 proposed or my organization proposed. Certainly during  
2 the Intel days, I had to do cost estimation for all the  
3 contracts that I negotiated, and these are very, very  
4 large contracts. The Samsung contract was greater than  
5 a billion dollars. So, we had to do very careful, very  
6 thorough cost estimations for those contracts.

7 We had to do very careful tracking of costs.  
8 In other words, we not only estimated the costs, but we  
9 were able to then see what the actual costs were during  
10 the components contracting operations.

11 And of course, at ISD, everything continued in  
12 the same vein except on a smaller scale.

13 Q. ISD being Information Storage Devices?

14 A. Information Storage Devices, yes.

15 Q. Did any of your experience give you any insight  
16 into the cost structures of DRAM manufacturers?

17 A. Clearly. Not only did I have the experience of  
18 Intel's DRAM manufacturing in the very -- in the early  
19 years, but as manager of -- as director of components  
20 contracting, I had the opportunity to evaluate --  
21 visit, evaluate and gather data at the various DRAM  
22 factories that we were using for contract  
23 manufacturing.

24 MR. DETRE: Your Honor, at this time we tender  
25 Mr. Geilhufe as an expert in semiconductor design and

1 manufacturing, including manufacturing costs.

2 JUDGE McGUIRE: Any objection?

3 MR. DAVIS: No objection, Your Honor.

4 JUDGE McGUIRE: All right, so qualified.

5 MR. DETRE: Thank you.

6 JUDGE McGUIRE: I just want to get that clear  
7 again, he's being offered as an expert in --

8 MR. DETRE: Semiconductor design and  
9 manufacturing, including manufacturing costs.

10 JUDGE McGUIRE: Okay.

11 BY MR. DETRE:

12 Q. Mr. Geilhufe, in this case we've heard a fair  
13 amount about four features of DRAM technologies,  
14 programmable latency, variable burst length, dual edge  
15 clocking and on-chip DLL.

16 Are you familiar with those technologies?

17 A. I'm familiar with the terms and the concepts,  
18 yes.

19 Q. Okay, let me show you a document.

20 May I approach, Your Honor?

21 JUDGE McGUIRE: Yes.

22 BY MR. DETRE:

23 Q. Mr. Geilhufe, I've handed you a document marked  
24 as CX-1454.

25 A. Yes.

1 Q. Let me just wait for it to come up on the  
2 screen. There we go.

3 Have you seen this document before?

4 A. Yes, I have.

5 Q. Have you reviewed it?

6 A. Yes, I have.

7 Q. I'll just note for the record that it's a  
8 document that we've been identifying in this case as  
9 either the PCT or the WIPO application that Rambus  
10 filed in 1991.

11 In your review of the PCT application, Mr.  
12 Geilhufe, did you reach an opinion as to whether all  
13 four of those features, programmable latency, variable  
14 burst length, dual edge clocking and on-chip DLL, are  
15 disclosed in this application?

16 A. I reached an opinion that certainly a -- an  
17 experienced designer or an experienced design manager  
18 would be concerned that those features are, indeed,  
19 described in the PCT application.

20 Q. And when you say a designer, are you talking  
21 about a DRAM designer?

22 A. Excuse me, a DRAM designer or a DRAM design  
23 manager.

24 Q. Have you reached an opinion as to whether those  
25 features, as described in this application, CX-1454,





1 Q. If you were working on designing an SDRAM  
2 incorporating programmable latency and burst length and  
3 came across the PCT application, what would you have  
4 done?

5 A. If I were the -- if I were in the role of the  
6 experienced designer, first of all, a caution flag  
7 would go up. I would -- I would study that topic to  
8 some extent, and I would then take my concern that the  
9 analysis would raise to my management and my peers for  
10 further analysis.

11 Q. And you've been in the role of a manager also,  
12 haven't you, Mr. Geilhufe?

13 A. Absolutely.

14 Q. If one of your designers had brought these  
15 concerns to you as a manager, what would you have done?

16 A. As a responsible manager, recognizing that  
17 we're dealing with a very, very large economic impact  
18 issue -- that is, if a DRAM design infringes a patent  
19 or potentially infringes a patent, it could use huge  
20 economic losses to the company -- as a responsible  
21 manager, I would then gather additional technical  
22 analysis from specialis0on 22gato3nalnen e3ehe areable

1 came back and said the concern has some validity, I  
2 would then take the issue to corporate counsel,  
3 corporate IP counsel or out-house -- outside IP counsel  
4 and get a careful review.

5 Q. Now, in your opinion, would an experienced DRAM  
6 designer reviewing this application, CX-1454, have  
7 believed that any IP -- any patent claims Rambus could  
8 get from this application would be limited to a  
9 particular bus architecture?

10 A. Not -- not an experienced designer.  
11 Experienced designers having some knowledge of  
12 intellectual property recognize that a particular --  
13 let's say a circuit in a particular patent cannot be  
14 used in some other patents.

15 A very good example, one of my patents was used  
16 in a totally different application and collected huge  
17 royalties for that application.

18 Q. Okay. Well, let me -- we can put this document  
19 aside.

20 These four features that we have now  
21 introduced -- and I won't repeat them each time -- in  
22 what part of DRAM are these four features implemented?

23 A. These are control features. They are the  
24 peripheral circuitry. They are not the memory part of  
25 the circuitry but the peripheral part of the circuitry.

1           Q.  And could you explain in a little bit more  
2 detail the difference between the -- what you call the  
3 memory part of the circuitry and the peripheral  
4 circuitry?

1 peripheral circuitry?

2 A. Yes. The memory arrays development includes  
3 device and cell development, process development and a  
4 lot of equipment development. That is the vast  
5 majority of the development cost. Hundreds of millions  
6 of dollars can be spent in that particular domain.

7 The development costs for the peripheral logic  
8 can indeed be significantly -- much, much lower,  
9 because there is no process development involved  
10 whatsoever.

11 Q. And if you could just briefly describe what you  
12 mean by "process development."

13 A. Process development is the manufacturing  
14 process that a silicon wafer undergoes, as many as 400  
15 or 500 steps, distinct steps, including  
16 high-temperature processing, photo processing, those --  
17 that is what is called the process, the manufacturing  
18 process.

19 Q. Now, Mr. Geilhufe, have we asked you to  
20 estimate the cost impacts of some of the alternatives  
21 to these four features we've been discussing that have  
22 been proposed by complaint counsel's technical expert,  
23 Professor Jacob?

24 A. Yes, you have.

25 Q. And have you made those estimates?

1 A. I have made those estimates, yes.

2 Q. Now, in making these estimates of the cost

1 Q. And --

2 A. And the requirement for that, of course, is to  
3 run a 20 million unit volume, you need to be well down  
4 the learning curve.

5 Q. Now, if you had not made this assumption about  
6 being well down the learning curve, would your cost  
7 estimates have been different?

8 A. They would have been much, much larger, because  
9 the cost -- the base costs would have been much larger.

10 MR. DETRE: Your Honor, we're going to be using  
11 a few demonstratives with Mr. Geilhufe. May I hand a  
12 set up?

13 JUDGE MCGUIRE: Yes, you may. Do we have those  
14 already marked?

15 MR. DETRE: Yes, we do. And I'll also hand a  
16 set to Mr. Geilhufe.

17 JUDGE MCGUIRE: Go ahead. You have one for  
18 opposing counsel, I assume.

19 MR. DETRE: I do. And we have, as I mentioned,  
20 premarked these with DX numbers, and if we could pull  
21 up the first one, DX-298, please, starting with the  
22 heading Cost Effect of CAS Latency Alternatives.

23 (DX Exhibit Numbers 298-301 were marked for  
24 identification.)

25 BY MR. DETRE:

1 Q. Mr. Geilhufe, does this chart summarize your  
2 opinions about the cost effects of certain alternatives  
3 to programmable CAS latency proposed by Professor  
4 Jacob?

5 A. Yes, it does.

6 Q. Did you assume any particular time frame when  
7 making these estimates?

8 A. The estimates for this -- excuse me, the time  
9 frame for this estimate was in mid-1995.

10 Q. Okay. And do you have some understanding of  
11 what the total unit cost of a DRAM was in that time  
12 frame?

13 A. The mature, first-tier total unit cost was  
14 approximately \$2, and that is what I used as my model.

15 Q. Now, if we look at the very top row of this  
16 chart, there are a number of headings, Process &  
17 Storage Cell/Array, Product Design and so forth.

18 Do you see that?

19 A. Yes, I do.

20 Q. What do these headings represent?

21 A. Those headings represent cost elements that I  
22 looked at in detail that are involved in a DRAM.

23 Q. And if we look down the very first column where

1           A. That column lists the five alternatives that I  
2       evaluated for CAS latency.



1 particular alternative, and that's what the "f" means.

2 Q. Now, over the course of your career, have you  
3 had the occasion to make cost estimates involving  
4 process and storage cell/array costs?

5 A. Yes, I have.

6 Q. Can you explain when that's come up?

7 A. The last one was at a 64K DRAM in the 1988 time  
8 frame.

9 Q. And if we could move on to the next column,  
10 Product Design, could you explain what comes under that  
11 heading?

12 A. Yes, this is the manpower required, the  
13 computer time required, the simulations required to go  
14 ahead and create a particular alternative.

15 Q. And there's an "f" after that one also.

16 A. Right, that is a one-time cost, and it would  
17 get amortized over the entire population that gets  
18 built.

19 Q. And again, over the course of your career, have  
20 you made cost estimates involving product design costs?

21 A. Yes. The design estimates I've made throughout  
22 my career, the last one I believe was in 1998 or '97.

23 Q. If we go to the next column, Wafer Plant, could  
24 you please explain what wafer plant costs involve?

25 A. Here I was trying to analyze whether new

1 equipment was required in the wafer factory to support  
2 the alternative.

3 Q. Okay. And is that a fixed cost also?

4 A. Exactly. That would be a one-time cost.

5 Q. Have you made cost estimates involving this  
6 cost factor in your career?

7 A. I have evaluated manufacturing -- excuse me,  
8 plant costs throughout the world through the entirety  
9 of my career, yes.

10 Q. The next column is Photo Tooling. Could you  
11 please explain that?

12 A. To process a silicon wafer requires reticles or  
13 photo tools, and this is the one-time cost that is  
14 required to create the tool for that particular  
15 alternative.

16 Q. Now, you mentioned reticles. In this case  
17 we've sometimes heard the term "masks." Is there some  
18 relationship between masks and reticles?

19 A. Yes, the mask term is -- us old guys use mask  
20 terms, the term "mask." That's what it was 20 years  
21 ago. "Reticle" is the much more refined, much more  
22 sophisticated term.

23 Q. And is that also a fixed cost?

24 A. That is a one-time cost for the population.

25 Q. Have you made cost estimates involving this

1 factor during your career?

2 A. I have not only made cost estimates, but I've  
3 purchased photo tooling throughout my career, and as --  
4 I -- the company on whose board I sit, one of the key  
5 elements is photo tool costs for their products.

6 Q. The next column is Wafer Sort. Could you  
7 please explain what you mean by wafer sort?

8 A. Yes. Once a wafer is processed --  
9 unfortunately, in the semiconductor industry, we don't  
10 build good units. We build lots of units, and then we  
11 decide a good die or we separate a good die from a bad  
12 die.

13 Wafer sort is the electrical test operation  
14 that identifies the good die on a wafer and rejects the  
15 bad die on a wafer.

16 Q. And under -- under Wafer Sort, you have a "v"  
17 in parentheses. Could you explain what that means?

18 A. Yes, that cost is really dependent on the  
19 number of units that are being processed. So, it is a  
20 per-unit cost as opposed to a fixed cost.

21 Q. What does "v" stand for?

22 A. Variable.

23 Q. Have you made cost estimates involving costs  
24 related to wafer sort in the course of your career?

25 A. Yes, throughout my career.

1           Q.  If we go to the next column, Good Die Yield,  
2  could you please explain that?

3           A.  Yes, probably the most important parameter in  
4  the life of a semiconductor businessman, it really  
5  identifies -- if you build a hundred units, do you get  
6  30 good ones or 90 good ones or 99 good ones?  The die  
7  yield is the percentage of good die versus die built.

8           Q.  And you've identified that as a variable cost?

9           A.  Again, yes, because that is literally -- it  
10 changes on a per-unit basis.

11          Q.  Okay.  And have you had the occasion to make  
12 cost estimates relating to good die yield over the  
13 course of your career?

14          A.  Throughout my entire career, throughout -- all  
15 the way through ISD, and I also had the opportunity to  
16 work many yield improvement programs over the years,  
17 which address exactly this issue.

18          Q.  The next column is headed Packaging.  Could you  
19 please explain what you mean by packaging?

20          A.  Yes, once we have a die and we decide it's a  
21 good die in wafer sort or potentially a good die in  
22 wafer sort, we take that die and put it through a  
23 manufacturing process that attaches leads to that die  
24 so that the -- a package can be put on the circuit  
25 board.



1 What do you include under that heading?

2 A. There are two elements in inventory. One is  
3 the work in process element; that is, in a factory, it  
4 may take six weeks or eight weeks to complete all the  
5 400 processing steps to create a finished wafer. That  
6 means you have work in process inventory sitting in  
7 that factory. If it's six weeks worth, you have six  
8 weeks worth of inventory. So, I include work in  
9 process inventory in fab, I include work in process  
10 inventory in the assembly plants.

11 And the second element of inventory is the  
12 finished product inventory; that is, once a product  
13 passes final test and is determined as a good unit, it  
14 then goes into finished goods inventory at the  
15 manufacturers. It may go into inventory in a  
16 distribution channel, and it definitely goes into  
17 inventory by the user itself. So, we have a complete  
18 food chain, if you will, of inventories. And I've  
19 attempted to identify that total cost.

20 Q. Okay. Have you treated that as a fixed cost or  
21 a variable cost?

22 A. I've treated it as a variable cost.

23 Q. Okay. Now, the next -- oh, excuse me, I almost  
24 forgot one of my questions.

25 Have you made cost estimates relating to



1       qualifies the particular line item, the particular  
2       product code.

3           Q.   Have you made cost estimates relating to  
4       qualification during your career?

5           A.   Of course.  I've not only made cost estimates,  
6       but I've ran a large number of qualifications when I  
7       was responsible for that function.

8           Q.   And then finally, the last factor listed is  
9       Board Complexity.  Please explain what that means.

10          A.   Yes, we're now out of the realm of the DRAM  
11       manufacturer, and we're in the space of the user.  So,  
12       if we changed a DRAM, for instance, we add more pins to  
13       it or something, that may require a larger board area,  
14       more real estate on the board, or it may require more  
15       traces or some other effect like that, and that is the  
16       effect that I was trying to establish with board  
17       complexity.

18          Q.   And you've identified that as a variable cost?





1           A. Yes, that symbol means approximate. Please  
2 recognize that this is a model, and all the numbers on  
3 the model, by its very nature, have to be approximate.

4           Q. Now, in making these estimates, have you tried  
5 to err on one side or the other?

6           A. Well, you will find as we go through here that  
7 generally I erred on the conservative side; that is,  
8 the lower cost increases side.

9           Q. Okay. So, under Product Design, you have got,  
10 "Add approximately 100K --" does K mean thousand?

11          A. \$100,000.

12          Q. "-- per CAS latency part."

13                 Could you explain why you've assigned \$100,000  
14 per CAS latency part under Product Design?

15          A. Yes, to create a new product requires a number  
16 of significant steps during the design effort. The  
17 actual design activity may be quite minimal, but it  
18 may -- it definitely will require the characterization,  
19 simulations work, and a minimum level in my experience  
20 in a large company is about \$100,000 to do a new line  
21 item, new product code.

22          Q. So, were you assuming that this was going to be  
23 a minor design effort or a major design effort or  
24 somewhere in between?

25          A. This is a minor design effort.

1           Q.  If we go to the next non-negligible column  
2  under Photo Tooling, you have got, "Add approximately  
3  \$50,000 per CAS latency part."

4                    Could you explain that?

5           A.  Yes, that is my estimate of the photo tooling  
6  cost required.

7           Q.  And what's that estimate based on?

8           A.  That's based on the cost of photo tools today.  
9  A photo tool set may cost between a million and a  
10 million and a half dollars.  This is the time frame

1           Q. Next, under Good Die Yield, you say, "Reduced  
2 yield due to speed distribution."

3                    Could you explain what you mean by "speed  
4 distribution"?

5           A. Yes. The semiconductor manufacturing process  
6 produces a distribution of results; that is, for  
7 instance, the access time of a hundred chips on a die  
8 may vary from 13, 14, 15, 16 nanoseconds. There will  
9 be a normal distribution, and that depends on a number  
10 of parameters, physical dimensions and what have you.

11           Q. Now, why would there be a reduced yield due to  
12 speed distribution if you went from programmable  
13 latency to fixed latency?

14           A. Pble

1 the test for the faster part will have some fall-out;  
2 that is, there will be die that are functionally  
3 working, but they're not fast enough for that  
4 particular specification, and they will be rejected.

5 Q. And what in your estimation would the cost  
6 effect be of this reduced yield due to speed  
7 distribution?

8 A. I have estimated that cost to be approximately  
9 3 cents or approximately 1 to 1.5 cents.



1 Q. Let's move on then to the next row in your  
2 chart, CAS latency in Read/Write Command. Could you  
3 explain what you mean by that alternative?

4 A. Yes. There were two versions, I believe, in  
5 Dr. -- in Professor Jacob's report, but basically it's  
6 to communicate the CAS latency value while the  
7 read/write command is issued.

8 Q. And then under that, you have -- excuse me, the  
9 first non-negligible number I see is under Product  
10 Design, "Add approximately \$100,000."

11 Could you explain that?

12 A. That's correct. I assumed a nominal or modest  
13 design effort to go ahead and create that product.

14 Q. And under Packaging, it says, "Negligible or  
15 add approximately 1 cent for added pin."

16 Could you explain that?

17 A. Yes, again, it's sort of the conservative  
18 approach that we have. Professor Jacob suggested one  
19 pin could be used for that aspect. In the packaging  
20 environment, one can't really add just one pin in a  
21 dual inline package; you have to add it in pairs. So,  
22 in reality, we should be adding two pins or at least  
23 the cost associated with two pins. So, I've added a  
24 cost of 1 cent if the pin is used.

25 Q. Okay. And what was your bottom line using

1 those numbers then on this alternative?

2 A. I then concluded that the alternative would  
3 increase costs from about one-half a cent to as much as  
4 2 cents.

5 Q. Let's move on then to your next row, which  
6 relates to programming CAS latency with fuses.

7 Do you see that?

8 A. Yes.

9 Q. And under Process & Storage Cell/Array, you  
10 have, "None if use existing fuse technology."

11 Can you explain what you mean by that?

12 A. Yes. Fuse technology is very important in the  
13 manufacture of DRAMs, certainly in the '95 time frame  
14 and still today. It's a critical element that is used  
15 to repair defective parts of the memory array.

16 In the '95 time frame, the dominant fuse  
17 technology used for that purpose -- and by "dominant,"  
18 I believe all the majors used it at that time -- is  
19 laser fuse technology, but I'm assuming here for this  
20 analysis is that if a fuse is used, it's a laser fuse,  
21 laser-blown fuse.

22 Q. What other fuse technologies are there other  
23 than laser fuses?



1 developing some products in that space which were  
2 discontinued at Intel for reliability reasons, and it's  
3 a very simple mechanism. You blow a fuse open, and  
4 over time and over operation, it has a tendency to  
5 migrate back together. So, it's not quite -- quite  
6 satisfactory.

7 In addition to that, there are anti-fuse  
8 technologies, both amorphous and dielectric, also with  
9 some fairly peculiar reliability concerns.

10 Q. What is your understanding of whether such  
11 anti-fuse technology was being used in DRAMs in the  
12 time frame mid-1990s when you were making these  
13 estimates?

14 A. For the mid-1990s time frame, I believe the  
15 major manufacturers were using laser fuses.

16 Q. Okay. And what is that belief based on?

17 A. My own personal experience with several of the  
18 Japanese and Korean manufacturers. I do not have any  
19 personal experience with Micron.

20 Q. Now, here you say under Process & Storage  
21 Cell/Array, "None if use existing fuse technology."

22 Do you have an opinion about whether there  
23 would be a cost associated with the process and storage  
24 cell/array factor if a manufacturer that was not using  
25 anti-fuses then were to begin using anti-fuse

1 technology for its fuses?

2 A. Yes, I do.

3 Q. What's that opinion?

4 A. Anti-fuse technology is not generally available  
5 in the DRAM process. It requires what's called a metal  
6 insulator or metal structure that is not generally  
7 available --

8 JUDGE MCGUIRE: Can we go back, and before you  
9 go into that, could you explain to the Court what you  
10 mean by "anti-fuse technology"?

11 THE WITNESS: Yes. Fuse technology -- fuse  
12 technology is you take a conductor, and just like a  
13 fuse at home, you blow it open, and in theory, it stays  
14 open. In reality, on an integrated circuit, it has a  
15 tendency to try to grow back together at some level.

16 Anti-fuse technology is the two -- the  
17 conductor is isolated, that is, there is no connection,  
18 and once you blow that fuse electrically, you create a  
19 connection. So, it is the inverse of a fuse.

20 JUDGE MCGUIRE: All right, Mr. Detre.

21 BY MR. DETRE:

22 Q. Now, the laser fuses that you were talking  
23 about earlier, can you use those either before or after  
24 packaging?

25 A. The laser fuses can only be used at wafer sort,

1 before packaging.

2 Q. Okay. And how about anti-fuses?

3 A. Anti-fuses could potentially -- if they were  
4 the right anti-fuses can potentially be blown after  
5 packaging.

6 Q. Okay. And you were I believe explaining what  
7 sort of costs might be involved in adding anti-fuse  
8 technology if a DRAM manufacturer did not have that  
9 available.

10 A. Yes. If the anti-fuse technology module does  
11 not exist in the DRAM process, adding that could be a  
12 significant cost, and by "significant," the development  
13 of that would be several million dollars in my opinion.

14 Q. Okay. Now, under the next column, Product  
15 Design, with respect to the fuse alternative, you have,  
16 "Add approximately \$100,000."

17 Could you explain that?

18 A. Yes, one would need a new mask set if one  
19 wanted to use fuse technology for programming.

20 Q. Now -- and does that relate to product design?

21 A. I'm sorry?

22 Q. I was asking you about the \$100,000 figure  
23 under Product Design.

24 A. That is correct.

25 Q. So, that's designing with the mask set?

1           A. No, it -- I apologize. I was getting in front  
2 of myself.

3           No, this is purely the design effort to go  
4 ahead and provide for the fuses. That's all.

5           Q. Okay. Now, under Wafer Plant and Photo  
6 Tooling, you have, "None if use existing fuse  
7 technology."

1 Q. And why is that?

2 A. Because again, once the fuse is blown, you have  
3 a fixed CAS latency part.

4 Q. Okay. And could -- and -- excuse me.

5 What is your opinion of how much cost that  
6 would add due to the reduced yield?

7 A. Approximately 3 cents.

8 Q. Three cents per unit?

9 A. Per unit, excuse me, yes.

10 Q. The next non-negligible cost you had was under  
11 Inventory, "Three parts add approximately 2 cents per  
12 unit."

13 Could you explain that?

14 A. Again, it's identical to a fixed CAS latency.  
15 At this point, we have fixed CAS latency parts, so it  
16 is the same as -- inventory cost as if we had built  
17 fixed CAS latency parts from scratch.

18 Q. Now, if I could stop here at inventory for a  
19 second, you have estimated approximately 2 cents per  
20 unit. Do you know of any actual cases involving  
21 inventory problems and associated costs?

22 A. Well, the DRAM industry is an interesting  
23 industry because of the cost reductions that take place  
24 in the industry over a relatively short time period. A  
25 64-meg DRAM in 1994 may be \$40 or \$50 in cost, and 12



1           Q. This Apple loss of \$27 million, do you know how  
2 that relates to -- if we were looking at that on the  
3 per-unit basis, how that relates to your estimate here  
4 of approximately 2 cents per unit?

5           A. Well, for Apple, it was probably a \$5 or \$6 per  
6 unit loss.

7           Q. Are you familiar, Mr. Geilhufe, with the term  
8 "speed binning"?

9           A. Of course.

10          Q. Could you explain what you understand that to  
11 mean?

12          A. Again, the manufacturing process turns out a  
13 distribution of performance; that is, access time of  
14 various levels. Speed binning is the testing process  
15 that says, yes, my part is faster than 15 nanoseconds,  
16 that's maybe bin one; my part is faster than 18  
17 nanoseconds, between 15 and 18, that's a bin two; and  
18 an 18 to 25, that's a bin three. That's what I  
19 understand to be speed binning.

20          Q. Okay. And that's something that DRAM  
21 manufacturers do?

22          A. Absolutely.

23          Q. Now, does the fact that DRAM manufacturers do  
24 this sort of speed binning, does that have any effect  
25 on inventory costs and having multiple parts?

1           A. Not -- not really. Consider that the slower  
2 part gets sold for a much lower price than the faster  
3 part, so the faster part carries a large premium over  
4 the slower part. So, I did not estimate or I did not  
5 include speed binning as an alternative, because it's  
6 too minor of a factor.

7           Q. Okay. Now, the next non-negligible item under  
8 Program CAS Latency With Fuses is under Qualification,  
9 you have, "Add approximately \$250,000 per CAS latency  
10 part."

11                    Could you explain that?

12           A. Yeah, again, at this stage, we have fixed CAS  
13 latency parts. Each part needs to be qualified.

14           Q. And could you then tell me what your bottom  
15 line is on what the cost effect would be of going to  
16 the programmable CAS latency with fuses alternative?

17           A. The alternative I modeled here is approximately  
18 7 cents cost increase.

19           Q. And that, again, combines the variable costs  
20 with the fixed costs the way you described before?

21           A. That is correct.

22           Q. Okay. If we go to the next alternative, CAS  
23 Latency Via Pins, do you see that?

24           A. Yes, I do.

25           Q. What's your understanding of that alternative?



1           A. The alternative is CAS latency is programmed  
2 with three bits in the program register, so we would  
3 have to provide three pins -- excuse me -- yes, we  
4 would have to provide three pins. Pins are added in a  
5 dual inline package in pairs of two. So, to add three  
6 pins would in reality require four pins.

7           Q. Okay. And then the first non-negligible entry  
8 you have there is under Packaging. Could you explain  
9 what your opinion is about how much this alternative  
10 would add to the packaging costs?

11          A. If we were to add four pins to the package, I  
12 modeled that as an increase of 4 cents. Again, one  
13 should recognize that that's a very conservative  
14 estimate. If we look at the JEDEC spec, the JEDEC spec  
15 generates -- moves from a 44-pin package, not to a 46  
16 or 48 for its next generation, but to a 54-pin package.  
17 So, in other words, the JEDEC spec goes and adds ten  
18 pins for the next generation. And then it actually  
19 moves to a 66-pin package, adding 12 pins. So, it adds  
20 it in larger increments. I modeled just adding the  
21 four pins here.

22          Q. Okay. And then under Board Complexity, you  
23 say, "May need different connector."

24                   What do you mean by a connector?

25          A. If we put four more pins on the memory and the

1 memory is on a DIMM, then now we need those four lines  
2 to go from the DIMM to the motherboard. If those four  
3 pins are no longer available on the connector, we may  
4 need a larger connector there, and that may increase  
5 that cost somewhat.

6 Q. Okay. Are there any other changes to the  
7 system that you would need in order to -- if you added  
8 four pins to the DRAM?

9 A. Of course. The controller would have to be  
10 modified, and I did not model that cost.

11 Q. Would you need more pins on the controller?

12 A. Of -- you would need more pins, and you would  
13 need a change in functionality.

14 Q. Okay. And would you need any other changes to  
15 the board?

16 A. And the board would have to -- the bus on the  
17 board would have to be increased by at least four.

18 Q. And so without adding any additional costs,  
19 then, that might have come from the controller or the  
20 board, what is your bottom line there on the

1           Q.   Okay.  Then if we could go to the last line on  
2 this chart, No CAS Latency Asynchronous DRAM, can you  
3 explain what you understand by that alternative?

4           A.   Yes.  Certainly in the early nineties,  
5 asynchronous DRAM was the standard way of producing  
6 DRAM, EDO DRAM, what have you, and if no CAS latency --  
7 no programmable CAS latency is required, we would  
8 reduce the test time, and that would be the only  
9 effect.

10          Q.   And how much do you think the test time would  
11 be reduced?

12          A.   I believe the test time would be reduced by  
13 approximately -- would -- the cost for test time would  
14 go down by approximately 1 cent.

15          Q.   Okay.  So, what then is your bottom line on  
16 that alternative of asynchronous DRAM?

1 (A brief recess was taken.)

2 JUDGE McGUIRE: You may proceed at this time,  
3 Mr. Detre.

4 MR. DETRE: Thank you, Your Honor.

5 BY MR. DETRE:

6 Q. Could we pull up DX-299?

7 Mr. Geilhufe, does this chart summarize your  
8 opinions about the cost effect of certain of the  
9 alternatives to programmable burst length proposed by  
10 Professor Jacob?

11 A. Yes, it does.

12 Q. Okay. Now, I -- did you assume any particular  
13 time frame when making these cost effect estimates?

14 A. Yes, I assumed the mid-1990s time frame, 1995  
15 approximately.

16 Q. Now, I will note that there are fewer factors  
17 listed on the top row of this chart than on the  
18 previous chart going to programmable CAS latency.  
19 Could you explain why that is?

20 A. Yeah, for clarity, we -- I removed the columns  
21 that were negligible through all the alternatives so  
22 that we would have a somewhat simpler chart here, still  
23 fairly complicated though.

24 Q. Okay. If we could go to the first row, then,  
25 relating to the fixed burst length alternative, could

1 you explain what you understand by that alternative?

2 A. Yes, that is -- the read command would ask for  
3 a fixed burst length as opposed to a programmable burst  
4 length.

5 Q. And if we look, then, at the first  
6 non-negligible entry under Product Design, "Add  
7 approximately \$100,000 per burst length part," could  
8 you explain that?

9 A. Certainly. You will find that fixed burst  
10 length is identical to fixed CAS latency. It has  
11 exactly the same characteristics. So, the \$100,000 is  
12 a design effort for each part type.

13 Q. Okay. And then the next entry under Photo  
14 Tooling, "Add approximately \$50,000 per burst length  
15 part," could you explain that?

16 A. Since the parts are different, each part needs  
17 a photo tool.

18 Q. And then under Wafer Sort, "Decreased test  
19 time," could you explain why there would be decreased  
20 test time?

21 A. Very much the same as for CAS latency; that is,  
22 if you only need to test for a -- for one burst length,  
23 that shortens the test time, and I assumed that would  
24 improve the cost by a penny, approximately a penny.

25 Q. And the next, under Inventory, you say, "Four

1 parts."

2           Why have you assumed that there were four  
3 parts?

4           A. The JEDEC spec calls for four parts.

5           Q. And what's your cost estimate of how much  
6 having four parts would add to inventory costs?

7           A. Inventory costs increase by the number of  
8 parts, and I modeled this particular level of  
9 inventory -- excuse me, line item increases increase  
10 the inventory costs, and I modeled for four different

1     before, by averaging the fixed costs over 20 million  
2     parts?

3             A. Over 20 million units, that is correct.

4             Q. If we could go then to the next row, Burst

1 if use existing fuse technology."

2           Could you explain that?

3           A. Again, just as for the CAS latency alternative,  
4 this assumes using laser-blown fuses.



1 corresponding number for CAS latency?

2 A. It is.

3 Q. What, then, is your bottom line for the  
4 alternative of programmable burst length with fuses?

5 A. I modeled this as a cost increase of  
6 approximately 5 cents.

7 Q. If we could then move to the next alternative,  
8 Fixing Burst Length With Terminate Command, do you see  
9 that?

10 A. I do.

11 Q. What is your understanding of that alternative?

12 A. It's -- I apologize. That is to program or --  
13 excuse me, to supply the -- to not have any burst  
14 length command at all, but to terminate the burst  
15 operation with a burst terminate command.

16 Q. Okay. And you have under Product Design, "Add  
17 approximately \$200,000."

18 Could you explain that?

19 A. Yes, I considered that the design effort would  
20 be considerably more complicated, and quite frankly, it  
21 may not even be possible to do a burst length of one  
22 with a terminate command, is just not possible.

23 Q. Could you explain why not?

24 A. Because a read command is issued or a write  
25 command, it takes one cycle to execute before a burst

1 terminate command could be encountered, and at that  
2 point, you already have two bits of data coming out.

3 Q. What, then, in terms of cost anyway, if it were  
4 technically feasible, what would the cost increase be  
5 of this alternative?

6 A. I modeled this cost increase purely as a design  
7 cost increase at approximately 1 cent.

8 Q. If we could go then to the next alternative,  
9 Burst Length Via Pins, is -- is your understanding of  
10 how this alternative works similar to your  
11 understanding of how you would set CAS latency via  
12 pins?

13 A. That is correct. Again, we would need three  
14 bits of information.

15 Q. Okay. Under Packaging, you say, "Add  
16 approximately 2 cents per unit."

17 Could you explain how you arrived at that  
18 figure?

19 A. Yeah, again, I used a conservative approach to  
20 modeling. Since we had a pin left over -- let me stop.

21 My assumption is that if pins are being used to  
22 program burst length, then they would also be used for  
23 programming CAS latency. We've already used four pins  
24 for CAS latency, so I only need two more pins to  
25 support the burst length. If the burst length were all

1 by itself, it would be four pins.

2 Q. And then under Board Complexity, is your  
3 opinion about the changes to the board and controller  
4 that would be required similar to your opinion about  
5 the corresponding alternative for CAS latency?

6 A. It is identical, yes.

7 Q. What, then, is your bottom line on the  
8 alternative of setting burst length using pins?

9 A. I modeled this cost as an increase of  
10 approximately 2 cents.

11 Q. If we could look then at the last row on this  
12 chart, Burst-EDO Style Protocol, what's your  
13 understanding of that alternative?

14 A. It's exactly the same as burst asynchronous  
15 DRAM in the CAS latency alternative. It's basically --  
16 I apologize. I'm getting in front of myself.

17 It is to use the asynchronous EDO-style memory.

18 Q. Okay. And is your opinion about the 1 cent  
19 cost decrease in that case similar to your opinion  
20 about the alternative of using asynchronous DRAM in the  
21 CAS latency alternative?

22 A. It is the same.

23 Q. Okay. If I could go back for just one second  
24 to the -- we are going to stay on this chart, but if I  
25 could go back to the top row, the fixed burst length

1 alternative, for one second, you had -- you had assumed  
2 four parts there, Mr. Geilhufe?

3 A. That's correct.

4 Q. And for fixed CAS latency, you had assumed  
5 three parts. Is that right?

6 A. Three parts for the SDRAM.

7 Q. If you were to go with the fixed CAS latency  
8 alternative instead of programmable CAS latency and the  
9 fixed burst length alternative instead of programmable  
10 burst length and you wanted to allow for all of the  
11 possible combinations of CAS latency and burst length  
12 allowed for in the JEDEC SDRAM specification, how many  
13 total parts would you need?

14 A. For the SDRAM, you would need 12 parts; that  
15 is, three times four. For the DDR RAM, you would need  
16 15 parts. The DDR RAM provides for five CAS latencies.

17 Q. How would that affect your cost estimates  
18 relating to fixed burst length and fixed CAS latency?

19 A. It would increase the -- well, first -- it  
20 would increase the inventory costs dramatically.

21 Q. Let's then go to DX-300, a chart headed Cost  
22 Effect of Dual-Edged Clock Alternatives. Does this  
23 chart, Mr. Geilhufe, summarize your opinion as to the

1 A. It does.

2 Q. And did you use any particular time frame in  
3 making these estimates?

4 A. Yes, for -- since this is through the DDR RAM,  
5 I used the late nineties time frame.

6 Q. Now, this chart has even fewer cost elements  
7 along the top. Could you explain why?

8 A. Again, the cost elements that were negligible  
9 for each of these alternatives were removed, were  
10 analyzed but were removed from the chart.

11 Q. Now, if we could look, then, at the first  
12 alternative, Interleave on-chip Memory Banks, two  
13 clocks, if -- if JEDEC had chosen this alternative  
14 instead of dual edged clocking, what's your opinion of  
15 how much that would have added to product design costs?

16 A. In my opinion, that is a more significant  
17 product design effort of the peripheral circuitry, and  
18 it would add approximately \$250,000 to implement that  
19 solution.

20 Q. Okay. And why is it a -- do you think it's a  
21 more sophisticated effort with respect to the  
22 peripheral circuitry?

23 A. Well, let's say the design effort is only in  
24 the peripheral circuitry, and it's a more sophisticated  
25 design effort compared to, let's say, a fuse, which is

1 a very simple design effort.

2 Q. Okay. Now, if we look under Good Die Yield,  
3 you say, "Reduced due to additional critical die area."

4 Do you see that?

5 A. Yes.

6 Q. What do you mean by "critical die area"?

7 A. As I described earlier, the memory component is  
8 about -- the active area is about 90 percent memory  
9 array. We have a unique technology called redundancy  
10 technology that can repair defective portions in the  
11 memory array. It's a very important part of the  
12 manufacture of DRAMs. And the way that works is the  
13 tester identifies a defective row or column or sector  
14 and replaces that with a spare sector that is  
15 functional. So, in essence, this large part of the die  
16 has some repairability associated with it, and a defect  
17 occurring there may not cause die failure.

18 The periphery does not have any redundancy  
19 capability. So, a defect in the periphery I call the  
20 critical die area, because a defect there will cause  
21 die failure.

22 Q. And why would this alternative reduce -- sorry.

23 Why would this alternative result in additional  
24 critical die area?

25 A. Because we are now taking two banks of data and

1 combining them. That's going to require some  
2 circuitry, some multiplexing circuitry, some timing  
3 circuitry, which is critical in nature.

4 Q. Okay. And what -- what is your opinion as to  
5 the cost effect of going with this alternative instead  
6 of dual edged clocking?

7 A. I reduced the die yield by approximately 2  
8 percent for this particular solution.

9 Q. Okay, and what --

10 A. And it costs -- and that costs approximately 3  
11 cents.

12 Q. Okay. If we could go, then, to the next  
13 non-negligible number under Final Test & Good Unit  
14 Yield, you say, "Increased Complexity testing."

15 Could you explain what you mean by that?

16 A. Yes, we now need to activate two banks, add  
17 some clocking circuitry. It may not be possible to  
18 test that as efficiently at wafer sort as if that  
19 circuitry were not there, and therefore, at final test,  
20 we have a slightly higher fall-out.

21 Q. Okay. And what would the cost effect of that  
22 higher fall-out be?

23 A. And I modeled that at a 2 cents cost effect  
24 increase.

25 Q. So, what, then, is your bottom line as to what

1 the estimated cost increase or decrease would have been  
2 if JEDEC had chosen this alternative instead of dual  
3 edged clocking?

4 A. I estimated the cost increase to be  
5 approximately 6 cents a unit.

6 Q. If we could go then to the next row, Interleave  
7 Memory Banks on DIMM, what's a DIMM, Mr. Geilhufe?

8 A. It's a dual inline memory module, a small  
9 circuit board that has 16 or 30 -- 16, 18 or 36 -- 32  
10 or 3 -- I can't -- 16 or 18 DRAMs on it.

11 Q. Sixteen or 18?

12 A. Yes.

13 Q. Are you sure it's not eight or 16?

14 A. Sixteen or 18.

15 Q. Sixteen or 18?

16 A. Yeah, the IBM versions, remember? A parity bit  
17 adds a memory.

18 Q. Oh, okay, got you.

19 Under Board Complexity, which is the only  
20 apparently relevant entry here, you say, "Add multiplex  
21 and driver circuits."

22 Could you explain why this alternative would  
23 require the addition of multiplex and driver circuits?

24 A. Clearly this alternative requires no change to  
25 the DRAM itself at all. It is only a requirement at



1 the DIMM level, where you now take two DRAMs and merge  
2 the data of the two DRAMs at the DIMM level together,  
3 and that requires multiplexing circuitry, similar to  
4 the circuitry that the first alternative has on board,  
5 but here it is a set of separate components and may  
6 require clock drivers also.

7 Q. And what in your opinion would adding that  
8 multiplexer and driver circuitry cost?

9 A. I estimated that cost to be approximately \$4  
10 for multiplexers and clock drivers.

11 Q. And how do you get from that to a per-unit  
12 cost?

13 A. Again, we used a 20 million unit --

14 Q. This is on the DIMM, right?

15 A. On the -- oh, thank you.

16 Q. No problem.

17 A. This -- since we're now on a DIMM, the one-time  
18 cost gets amortized over 16 memory components, which is  
19 the smallest number of units -- memory components on  
20 the DIMM, and that's how we arrive -- I arrived at the  
21 25 cent increase in cost.

22 Q. \$4 divided by 16?

23 A. That is correct.

24 Q. If we could go then to the next row, the Double  
25 DRAM Data Width from x16 to x32, do you see that?

1 A. Yes.

2 Q. What's your understanding of that alternative?

3 A. My understanding is we would take a DRAM that  
4 has 16 I/O pins or a bus of 16 I/Os and add an  
5 additional 16, in other words, double the data width.

6 Q. So, under Product Design, you have, "Add  
7 \$250,000."

8 Could you explain that?

9 A. Yes, this now requires significant redo of the  
10 peripheral circuitry, adding 16 I/O drivers and the  
11 necessary timing and multiplexing associated with that.

12 Q. And then under Good Die Yield, you have,  
13 "Reduced due to additional critical die area."

14 Could you explain what that means?

15 A. Yes, to add the additional I/O circuitry takes  
16 a considerable amount of critical die area, and I  
17 modeled that amount of die area to be -- to cost about  
18 5 cents.

19 Q. Okay. Then if we go on to the Packaging  
20 column, you say, "Use BGA."

21 What does BGA mean?

22 A. If we add 16 I/Os to the package -- I'm sorry,  
23 I'm not answering your question. BGA means ball grid  
24 array package.

25 Q. And what is that?

1           A. That is a type of package that can have many  
2 more pins than the dual inline or JEDEC TSOP package.

3           Q. And why in your opinion would you have to use  
4 that type of packaging?

5           A. The largest TSOP package that JEDEC specified  
6 was 66 as a standard industry standard package. To add  
7 16 pins, one -- it is my belief that one would have to  
8 go to a ball grid array package.

9           Q. And how much would that cost?

10          A. And I modeled that cost at 25 cents.

11          Q. So, then, in your opinion, if JEDEC had chosen  
12 this doubling DRAM data width alternative instead of  
13 dual edged clocking, what would the bottom line cost  
14 effect have been?

15          A. The bottom line cost effect would have been a  
16 31 cent increase, approximately, per unit.

17          Q. Let's move on then to the next row, Double  
18 Clock Frequency. Could you explain what you understand  
19 by that alternative?

20          A. My understanding is instead of using, let's  
21 say, a 200-megahertz clock, use a 400-megahertz clock.

1 receding circuitry, so there's a nominal design change  
2 that has to take place.

3 Q. Under Final Test & Good Unit Yield, you have,  
4 "Higher speed testing."

5 Could you explain what higher speed testing  
6 would be required?

7 A. Yes, because we are operating the clock at  
8 twice the speed than current technology, that is a  
9 significant step up in testing, and the test equipment  
10 changes significantly. Test equipment changes and  
11 yield changes would result.

12 Q. And what would the cost effect of that higher  
13 speed testing be?

14 A. The higher speed testing would result in  
15 approximately a 4 cent increase in yield and test  
16 costs.

17 Q. And then under Board Complexity, you have,  
18 "On-DIMM clock required."

19 Could you explain what you mean by that?

20 A. Yes. To distribute this much higher frequency  
21 signal on -- the double frequency signal on the DIMM  
22 would require a -- an on-DIMM clock circuitry, possibly  
23 on-DIMM PLL/DLL.

24 Q. And how much would that add to the cost?

25 A. I estimated that cost based on product

1 availability from various manufacturers at  
2 approximately the \$3.80. That cost is a very strong  
3 factor of frequency. Some of these parts can cost as  
4 much as \$7 or \$8 at high frequencies and can be less  
5 than this at low frequencies.

6 Q. And then what is your bottom line about what  
7 the cost effect would have been if JEDEC had chosen to  
8 double the clock frequency instead of using dual edged  
9 clocking?

10 A. I estimated the cost increase to be 28 cents  
11 approximately.

12 Q. A 28 cent increase?

13 A. A 28 cent increase, approximately.

14 Q. And then if we go to the last row on this  
15 chart, Asynchronous Toggle Mode, do you see that?

16 A. Yes.

17 Q. What is your understanding of the asynchronous  
18 toggle mode alternative?

19 A. That is basically to stay with the mid-'95  
20 technology of asynchronous DRAMs. Of course, the  
21 general wisdom at the time was that that was not  
22 feasible, but I made a real attempt to see if it could  
23 be designed, and it -- I made some very basic  
24 assumptions as to how much work it would take to design  
25 it.

1 Q. Okay. And under Product Design, you have, "Add  
2 approximately \$250,000."

3 Could you explain that figure?

4 A. Yes, this -- again, it's similar to the Double  
5 DRAM Data Width column -- excuse me, row. It's a  
6 significant design task.

7 Q. Under Good Die Yield, you say that would be  
8 reduced due to additional critical die area. Could you  
9 explain why that additional critical die area would be  
10 required?

11 A. We'd have considerable additional critical die  
12 area, and I modeled this as a 10 cent increase.

13 Q. Okay. And under Packaging, you say,  
14 "Additional pin."

15 Why would an additional pin be required?

16 A. Professor Jacob suggested that in his solution,  
17 and I modeled that.

18 Q. Okay.

19 A. Notice I modeled it only as a single pin, not  
20 the two pins that would likely be required in a TSOP  
21 package.

22 Q. Okay. And then what, then, is your bottom line  
23 conclusion about what the cost effect would have been  
24 if JEDEC had gone with asynchronous toggle mode instead  
25 of using dual edged clocking?

1           A. I estimated that cost increase to be  
2 approximately 12 cents.

3           Q. Let's move on then to the next chart, DX-301,  
4 and does this chart summarize your opinion, Mr.  
5 Geilhufe, about the cost effect of certain of Professor  
6 Jacob's alternatives to using an on-chip PLL or DLL?

7           A. Yes, it does.

8           Q. Okay. The first row, Double DRAM Data Width,  
9 is that essentially the same as the double DRAM data  
10 width alternative that you discussed with respect to  
11 dual edged clocking?

12          A. Exactly. It is exactly the same.

13          Q. And what is your conclusion then about how much  
14 that alternative would cost?

15          A. That alternative would increase the cost by  
16 approximately 31 cents.

17          Q. Let's move on, then, to the second row on this  
18 chart, Move DLL to DIMM. Could you explain what you  
19 understand that alternative to mean?

20          A. To take the DLL circuit block and remove it  
21 from the DRAM and add a set of circuits that carry the  
22 same functionality at the DIMM level.

23          Q. Okay. Now, under Wafer Sort, you say that test  
24 time would be decreased. Why is that?

25          A. Well, we remove a fairly sensitive circuit

1 block, the DLL on chip. That takes time to test. We  
2 reduce that -- we remove that test time.

3 Q. What would the cost effect --

4 A. And that would decrease the cost by 2 cents in  
5 my opinion.

6 Q. Okay. Under Good Die Yield, you say that there  
7 would be a slight yield increase. Can you explain  
8 that?

9 A. Again, the DLL is -- would be a critical die  
10 area, and I would assume that would increase the sort  
11 yield somewhat and would improve the cost by  
12 approximately 1 cent.

13 Q. Okay. And then finally, under Board  
14 Complexity -- should that be red under Board  
15 Complexity?

16 A. Yes, I apologize. We got the color wrong.

17 Q. Well, I am not sure that you were responsible  
18 for the colors, but in any case, why would an on-DIMM  
19 DLL be required here?

20 A. That, of course, is the alternative that  
21 Professor Jacob offers here.

22 Q. Okay. And how much would that cost?

23 A. And the on-DIMM DLL, again, would cost  
24 approximately \$3.80 on -- for the DIMM and would be  
25 then a function of the frequencies that were supported.



1           Q.   Okay.  And then how would you translate that  
2 into a per-unit cost?

3           A.   I would divide the \$3.80 by 16, that is,  
4 amortize it over 16 DRAMs, and then, of course, reduce  
5 that number by the improved test time and yield  
6 numbers.

7           Q.   Okay.  And then once you've done that, then,  
8 what is your bottom line about what the cost effect  
9 would have been if JEDEC had chosen to go with a DLL on  
10 the DIMM instead of an on-chip PLL or DLL?

11          A.   I modeled that cost as a cost increase of  
12 approximately 21 cents, approximately.

13          Q.   Now, Mr. Geilhufe, if you were going to  
14 implement one of the alternatives for on-chip DLL and  
15 another alternative for dual edged clocking that we've  
16 discussed and yet some other alternatives for  
17 programmable latency and burst, how would you calculate  
18 the total cost effects?

19          A.   The cost effects would all be additive.

20          Q.   Now, have you reached any opinions about the  
21 difficulty or ease of actually implementing the  
22 alternatives that you considered, assuming that they  
23 were technically feasible?

24          A.   Yes, I considered that in the design phase of

1 analysis.

2 Q. Okay. When could these alternatives be most  
3 easily implemented if you were going to try to  
4 implement them?

5 A. In DRAM manufacturing, there is a routine  
6 improvement -- the way costs are improved is by making  
7 changes to the product and the process on an as-needed  
8 basis, and that can happen as often as every six months  
9 or six to twelve or six to eighteen months. Every time  
10 one of these changes for either yield or process  
11 reasons are implemented, many of these if not all of  
12 these alternatives could possibly be implemented if  
13 they're technically feasible.

14 Q. Okay.

15 Thank you, Mr. Geilhufe, that's all I have.

16 JUDGE MCGUIRE: Thank you, Mr. Detre.

17 At this time, we will hear the cross  
18 examination by complaint counsel. Mr. Davis?

19 MR. DAVIS: Let me try to operate the ELMO for  
20 a second, because I have a question about the slides.  
21 If I could have a minute or two just to learn how to do  
22 that.

23 (Pause in the proceedings.)

24 CROSS EXAMINATION

25 BY MR. DAVIS:

1           Q. Just a quick question about the slides, I  
2 didn't quite understand. Well, that's actually good  
3 enough for my purposes, because I just need to ask you  
4 about the colors.

5           I understand the red, that's -- you think the  
6 cost goes up, so that's red.

7           A. Yes.

8           Q. And green, you think the cost goes down, so  
9 that's green.

10          A. That's right.

11          Q. I'm a little confused about the yellow and the  
12 gray, however. What does the yellow refer to?

13          A. It's just to help us delineate one row from the  
14 next. It has no significance.

15          Q. Okay. So, the gray is to delineate from the  
16 yellow, okay. I will take that off for now.

17                 Now, prior to your report in this case, Mr.

1 Exhibit B of your report prior to writing your report?

2 A. Yes, I did.

3 Q. And those references listed in Exhibit B, those  
4 are the documents that you relied on in putting  
5 together your opinions, in addition to your experience?

6 A. I primarily relied on my experience and my  
7 knowledge, industry knowledge.

8 Q. Okay. Your opinions didn't depend on any  
9 communications you had with Rambus attorneys?

10 A. They did not depend on any communication with  
11 Rambus attorneys.

12 Q. And they didn't depend on any communications  
13 you had with Rambus employees?

14 A. They did not depend on any communications with  
15 Rambus employees.

16 Q. And your opinions didn't depend on any  
17 communications you had with any other experts in the  
18 case?

19 A. They did not -- they did not depend on them,  
20 no.

21 Q. There were no documents that you wanted to see  
22 that you didn't get a chance to see prior to submitting  
23 your report?

24 A. I would have wanted to see cost documents from  
25 a number of companies, but no documents that were



1           MR. DAVIS:  If he wasn't going to say it, I  
2  wasn't going to bring it up.

3           JUDGE McGUIRE:  Okay.

4           BY MR. DAVIS:

5           Q.  You also reviewed the Jacob rebuttal report  
6  prior?

7           A.  Yes, I did.

8           Q.  YoD†       Tsa       A. w0 .rQ. rort )TjT\* Ja9

1 before your own deposition, made you think you needed  
2 to do any more work to confirm your conclusions in your  
3 report?

4 A. That is correct, nothing.

5 Q. Okay. And nothing you read in Dr. Peisl's  
6 deposition made you think you needed to do any more  
7 work to confirm your conclusions?

8 A. That is correct.

9 Q. Now, after your deposition but prior to your  
10 testimony here today --

11 A. Yes.

12 Q. -- have you read any additional deposition  
13 transcripts other than your own?

14 A. I've reviewed a whole series of documents, and  
15 quite frankly, I don't remember what they all are. I'm  
16 not very good at names.

17 Q. I think most of the engineers we've had so far  
18 haven't been so good with the names.

19 A. I'm one of them.

20 Q. Do you recall any additional deposition  
21 transcripts that you did review?

22 A. Let's see, there were various ones, and I just  
23 don't recall the specifics right now.

24 Q. You don't recall any names?

25 A. I think the -- the -- the Becker one -- yeah,

1 Becker, the deposition of the fellow from Siemens --  
2 from Infineon.

3 Q. The DRAM fabrication plant manager is who  
4 you're referring to?

5 A. Yes.

6 Q. Have you been reading the trial transcript?

7 A. I'm sorry, I -- I believe it was the trial  
8 transcript of Dr. -- of Mr. Becker, not the deposition.

9 JUDGE MCGUIRE: Now, let's be clear here for  
10 the record. You're talking about the trial in Infineon  
11 or the trial here at -- the FTC proceeding?

12 MR. DAVIS: Well, I'll clarify that.

13 BY MR. DAVIS:

14 Q. When you're saying you read the trial  
15 transcript of Mr. Becker, you are referring to the  
16 trial transcript in this case?

17 A. I believe that was it. I -- I'm not well  
18 versed in all the labels, but I believe that was it.

19 Q. I think that's the best we are going to be able  
20 to do.

21 Now, have any other facts or have any facts  
22 come to your attention that made you think you needed  
23 to do any additional work to confirm your conclusions  
24 in this case?

25 A. No.



1           Q. Now, what did you do to ensure that the  
2 analysis that you did was the type of analysis that's  
3 done at JEDEC?

4           A. I did not do anything. I did my analysis which  
5 has proven to be quite successful over the years.

6           Q. You never reviewed any JEDEC meeting minutes?

7           A. I did not.

8           Q. You never reviewed any JEDEC policy manuals?

9           A. I did not.

10          Q. You never spoke to any JEDEC employees to

1 Q. Well, there's both JEDEC employees, Mr.  
2 Geilhufe, and JEDEC members.

3 A. Oh, I see. I spoke neither to JEDEC employees  
4 nor JEDEC members.

5 Q. I was just about to make that clarification  
6 myself.

7 A. Thank you.

8 Q. And you never spoke with Rambus' JEDEC  
9 representative?

10 A. I did not.

11 Q. Did you ever ask to speak with Rambus' JEDEC  
12 representative?

13 A. No, I did not.

14 Q. Okay.

15 A. I felt I could give a much better opinion  
16 without hearing what someone who has a strong opinion  
17 feels.

18 Q. Now, have you ever been to JEDEC yourself?

19 A. I -- yes, I attended a -- one JEDEC meeting a  
20 long time ago.

21 Q. Now, I'm not sure -- are you confusing a JEDEC  
22 meeting with an IEEE meeting?

23 A. I believe I attended a JEDEC meeting once.

24 Q. Because when I asked you that question at your  
25 deposition, you said that you had never attended any



1 responsible for memory development.

2 Q. Now, when I asked you that question in your  
3 deposition, you told me that you had never supervised  
4 anybody who had --

5 A. I didn't, but there was someone in my  
6 organization, not someone I supervised.

7 Q. Okay.

8 JUDGE McGUIRE: You're talking about the  
9 organization at Intel?

10 THE WITNESS: At Intel, yes.

11 BY MR. DAVIS:

12 Q. Now, the only person you remember supervising  
13 whose job responsibility included attending  
14 standard-setting organization meetings was an employee  
15 of Intel who briefly reported to you in this time  
16 frame, sometime in 1975?

17 A. Oh, I think you're referring to Dick Pashley  
18 and the nonvolatile activity, yes. Thank you for  
19 reminding me.

20 Q. I want to go back to your background a little  
21 bit. So I understand, and I want to make sure I've got  
22 my notes right, the last time you contributed to a DRAM  
23 design was sometime in the mid to late 1980s. Is that  
24 right?

25 A. It depends on what you mean by "contribute." I



1 other companies' products to build them, brand them







1 factories and the skills of the people.

2 Q. Now, you were saying that a DRAM manufacturer  
3 can only use their factory for a relatively short time  
4 period for DRAM, something like one, two, three years.  
5 Is that right?

6 A. Yeah, not one year. It's longer than one year,  
7 but it's a finite life, and the life is shorter than  
8 the life of the -- clearly the building or the  
9 equipment.

10 Q. So, they use -- they use that same factory for  
11 other products?

12 A. Exactly.

13 Q. The fabrication plant that you were referring  
14 to in your work with ISD, you said you worked with a  
15 DRAM fab?

16 A. Um-hum, yes.

17 Q. That was the Kihun 1 fab. Is that it?

18 A. Yeah, Kihun 1 was a fab that went through that  
19 transition, and I also went through that transition on  
20 Kihun 2.

21 Q. And those were the fabs you were talking about  
22 when you said you had experience with DRAM fabrication  
23 plants when you were at ISD. Is that right?

24 A. That is correct.

25 Q. And the Kihun 2 fab -- am I pronouncing that

1 right, "Kihun"?

2 A. "Kihun" is close.

3 Q. That's as close as I can get.

4 Kihun 2, that was put together -- that was  
5 constructed, I'm sorry, in 1985. Is that right?

6 A. '85 or '86, that was definitely in that time  
7 frame.

8 Q. And the Kihun 1 fab was --

9 A. Was earlier, it was before that.

10 Q. Kihun 1 was built before?

11 A. Yes.

12 Q. Was it like 1982-1983, something like that?

13 A. Let's see, my first visit to that fab was  
14 somewhere in '84, somewhere in that time period.

15 Q. So, before '84?

16 A. Yes.

17 Q. Now, one of your opinions in this case that you  
18 gave this morning involved an analysis of the Rambus  
19 patent application along with the JEDEC standard. Do  
20 you remember that from this morning?

21 A. Analysis of the PCT application.

22 Q. Yes, that's what I was referring to.

23 A. Okay.

24 Q. I actually wrote '898 on my notes.

25 Going to the conclusions you reached on the

1 patent application, you read that patent application  
2 along with the JEDEC standard. Is that right?

3 A. That is correct. I only reviewed those two  
4 documents.

5 Q. And the conclusions you reached that -- I'm  
6 sorry, strike that.

7 The conclusions you reached were that some of  
8 the technologies described in the JEDEC standard are  
9 similar in form and function to some of the  
10 technologies described in the Rambus patent  
11 application?

12 A. That's correct, that's what I -- yes.

13 Q. And by "similar in form," you mean either an  
14 architectural characteristic or physical characteristic  
15 is similar between the JEDEC standard and the patent  
16 application?

17 A. Architectural context, application context or  
18 circuit context.

19 Q. When you said "application context," what did  
20 you mean by that?

21 A. For instance, a mode register, the concept of

1 A. And -- of course, they are.

2 Q. So, by "similar in function," you mean that if  
3 someone -- if something does one thing in the patent  
4 application, the PCT application, and it does the same  
5 thing in the standard, that the functions are similar?

6 A. I'm sorry, I don't think I understand.

7 Q. Okay, I'll say it -- I'll ask the question  
8 again.

9 By -- you found that -- you believed that the  
10 functions in the patent application, the PCT  
11 application, and the standard were similar in form and  
12 function, and I'm trying to understand what you mean by  
13 "form" and what you mean by "function."

14 So, I'm asking you by "function" --

15 A. Yes.

16 Q. -- do you mean that -- do you mean that if  
17 something does one thing in the patent application and  
18 it does the same thing in the standard, that the  
19 functions are similar?

20 A. That is correct. I -- yes.

21 Q. Now, you thought that it was irrelevant that  
22 the engineers who might have read the patent  
23 application --

24 THE REPORTER: I'm sorry, I didn't hear the end  
25 of that.

1 BY MR. DAVIS:

2 Q. I'll reread the question.

3 You thought that it was irrelevant that the  
4 engineers who might have read the patent application  
5 were at JEDEC. You didn't consider that as part of  
6 your conclusions.

7 A. That has no bearing on my analysis. My  
8 analysis was to review the documents.

9 Q. So, you didn't consider what effects the JEDEC  
10 patent disclosure rule would have had on the analysis  
11 done by the JEDEC representatives?

12 A. I did not.

13 Q. And you didn't consider the effects of what the  
14 good faith obligations on JEDEC members had on the  
15 expectations of its members?

16 A. I did not. I only considered what a designer  
17 or a design manager would do by being confronted by the  
18 two documents.

19 Q. You didn't consider the effects of Rambus'  
20 behavior at JEDEC on the analysis done by the JEDEC  
21 representatives?

22 MR. DETRE: Objection, Your Honor. The witness  
23 has asked and answered. The witness already answered  
24 what he did, that he did not consider any JEDEC stuff.

25 MR. DAVIS: I'm asking specific --

1 JUDGE McGUIRE: Well, this is another question,  
2 so I'll entertain this new question. Overruled.

3 BY MR. DAVIS:

4 Q. You didn't consider the effects of Rambus'  
5 behavior at JEDEC on the analysis done by the JEDEC  
6 representatives?

7 A. I did not consider it, and I have no knowledge  
8 of their behavior.

9 Q. And you didn't consider the potential impact of  
10 other information that the engineers at JEDEC might  
11 have had about Rambus?

12 A. Of course not. I only compared two documents.

13 Q. Okay. Now, I'd like to show you a document  
14 that's been marked as CX-1309, which is a Rambus  
15 technology and applications overview.

16 May I approach, Your Honor?

17 JUDGE McGUIRE: Yes.

18 THE WITNESS: Oh, boy.

19 BY MR. DAVIS:

20 Q. You won't be going through all those pages.

21 Could you turn to page 28 of CX-1309? Now,  
22 what you are looking for in terms of the page numbers  
23 are on the corner, do you see the page numbers there?  
24 It says CX-1309-028?

25 A. There we go, got it. Twenty-eight.

1 Q. Twenty-eight.

2 A. Okay.

3 Q. And do you see that there's a diagram on the  
4 left --

5 JUDGE McGUIRE: All right, now, before we get  
6 into that, I am going to need to know exactly what this  
7 document is for the record, Mr. Davis, so could you lay  
8 a foundation?

9 BY MR. DAVIS:

10 Q. Okay, this is a -- as I understand it, a Rambus  
11 technology and applications overview. I mean, we have  
12 seen documents like this.

13 A. Excuse me, sir, I didn't understand the answer.

14 JUDGE McGUIRE: Could you restate what this  
15 document is for the witness?

16 MR. DAVIS: Sure.

17 BY MR. DAVIS:

18 Q. This is a Rambus technology and applications  
19 overview, a description of the Rambus technology, and  
20 on page 28, do you see that there's a diagram on the  
21 left-hand side that's labeled SDRAM?

22 A. Yes.

23 Q. And a diagram on the right labeled RDRAM?

24 22 A. Yes.

Waldorfcorarylft-on?

1 diagrams like it on the question of how an experienced  
2 engineer at JEDEC would view the Rambus patent?

3 A. Of course not. As I indicated earlier, I only  
4 considered the JEDEC specification, JC-21, and the PCT  
5 application.

6 Q. Had you ever seen a diagram like this before?

7 A. I've seen thousands of diagrams.

8 Q. Do you recall seeing a diagram like this  
9 before?

10 A. I have never seen this diagram, no.

11 Q. Okay. Now, could you turn to page 212 of  
12 CX-1309? Again, it's the same page numbering.

13 A. Bear with me.

14 Q. Sure.

15 A. I've got it.

16 Q. Do you see there's a column on the left-hand  
17 side describing RDRAMs and a column on the right-hand  
18 side describing SDRAMs?

19 A. Yes, I do.

20 Q. Did you consider the effects of this table or  
21 tables like this on the question of how an experienced  
22 engineer would read the Rambus patent?

23 A. As I said, I have only reviewed the JEDEC  
24 document and the PCT application.

25 Q. Okay, you can put that aside.





1 application, you were able to identify the four  
2 features that you were asked to identify in that patent  
3 application?

4 A. As I indicated in my report, yes, I was able to  
5 identify that an experienced DRAM designer should --  
6 would show concern and would evaluate very carefully  
7 whether he could go ahead with some of these features.

8 Q. I'd like to talk a little bit about your  
9 conclusions regarding programmable burst length.

10 A. Okay.

11 Q. In your testimony, you stated that an  
12 experienced DRAM designer would find commonality  
13 between the variable block size of the PCT and the  
14 programmable burst length of the mode register. Is  
15 that accurate?

16 A. That's correct.

17 Q. And by "programmable burst length of the mode  
18 register," you were referring to the mode register  
19 that's described in JEDEC's standard 21-C, Release 9?

20 A. That is correct.

21 Q. And part of that standard is actually  
22 referenced, isn't it, in your Appendix B to your  
23 report? It's one of the documents you relied on.

24 A. That is correct.

25 Q. And by "variable block size," you're referring

1 to a particular bit of language from the PCT  
2 application. Is that right?

3 Let me read to you something from your -- from  
4 your report that --

5 A. Please.

6 Q. -- related to that same opinion, and it's going  
7 to be complicated because it's patent language, so we  
8 are going to have a lot of open parens and stuff. I'll  
9 try to be clear.

10 A. Can I have a copy of my report, please?

11 Q. Absolutely, absolutely.

12 A. Thank you.

13 Q. I should have done that first, I'm sorry.

14 A. Thank you.

15 MR. DAVIS: May I approach, Your Honor?

16 JUDGE McGUIRE: Go ahead.

17 THE WITNESS: Thanks.

18 BY MR. DAVIS:

19 Q. And in fact, for your reference, I'm referring  
20 to something that's on page 6 of your report.

21 A. Thank you.

22 Q. Paragraph 17.

23 Your Honor, we don't have this in the database,  
24 I don't think, so may I approach?

25 JUDGE McGUIRE: Yes, okay, that will be fine.

1 BY MR. DAVIS:

2 Q. Okay, "Page 27, (23) block size [0:3] Specifies  
3 the size of the data block transfer," and you have  
4 three dots, "if block size one is zero, then the  
5 remaining bits give a block size to the power of two."

6 Now, actually, in your deposition, you have a  
7 slight correction to the report language, right, which  
8 was that "block size one is zero" should actually read  
9 "block size zero is one." Is that right?

10 A. That's correct.

11 Q. But with that correction, your report describes  
12 your opinion in this area?

13 A. That is correct.

14 Q. Now, in your analysis, you identified three  
15 factors that were relevant to your opinion that an  
16 experienced DRAM engineer would find commonality  
17 between the variable block size in the PCT and the  
18 programmable burst length of the mode register. Is  
19 that right?

20 A. Yes, I did.

21 Q. And those three factors were the diagram in one  
22 document looks like the diagram in the other, the two  
23 documents use the same word, and they describe the

2and ms7ze to the power of yd- and they describe gh3srhe een the varia

1 so I can't vouch for it, but it sounds right.

2 Q. Okay. Well, why don't I give you a copy --

3 JUDGE McGUIRE: Mr. Detre?

4 MR. DETRE: Your Honor, I just object generally  
5 to the use of this expert report. It is not evidence.  
6 It can be used to impeach, but that's not how Mr. Davis  
7 is using it.

8 JUDGE McGUIRE: Mr. Davis, that's correct, so  
9 how do you intend to proceed in this matter?

10 MR. DAVIS: Well, Mr. Geilhufe described his  
11 conclusions in this matter regarding the patent  
12 application, but he didn't describe the basis in his  
13 testimony. He did describe the basis for that  
14 testimony in his report.

15 JUDGE McGUIRE: Then to that extent you can  
16 inquire.

17 MR. DAVIS: Thank you, Your Honor.

18 BY MR. DAVIS:

19 Q. Actually, I think I should give you a copy of  
20 your deposition as well on this.

21 A. Thank you.

22 MR. DAVIS: May I approach?

23 JUDGE McGUIRE: Yes.

24 BY MR. DAVIS:

25 Q. Now, the two documents use different words to

1 describe this concept, correct? I mean, one uses  
2 "programmable burst length," the other one uses  
3 "variable block size," so they're different terms.

4 A. Different terms describing the exact same  
5 function.

6 Q. Now, I'd also like to show you document CX-234,

1           A.  There's something out of whack on mine.  I have  
2   a 146 and then a 176.  The 150 doesn't seem to be  
3   there.

4           Q.  Why don't I give you this copy.  This copy has  
5   it.

6           May I approach?

7           JUDGE McGUIRE:  Go ahead.

8           THE WITNESS:  A bigger copy.  Thank you.

9           BY MR. DAVIS:

10          Q.  We're looking at page 150.

11          A.  I have 150.

12          Q.  You have 150 in front of you now?

13          A.  Yes.

14          Q.  This is the diagram of the mode register that  
15   you were referring to, is it not?

16          A.  That's correct.

17          Q.  Now, I'm going to give you another document,  
18   and I have to apologize for it, because you already  
19   have the document in another form, but it's RX-185,  
20   which is the PCT again.  My references on my outline  
21   are to that.

22          A.  Is there some question on the JEDEC document?

23          Q.  There is no question yet.

24          A.  Oh.

25          MR. DAVIS:  May I approach?

1 JUDGE McGUIRE: Yes.

2 BY MR. DAVIS:

3 Q. Now, could you turn to page 29 of RX-185, and  
4 by 29, I'm referring to the exhibit page numbers.

5 A. The exhibit page number is 29 and the document  
6 number is 27?

7 Q. I believe that's right.

8 A. Okay.

9 Q. Now, could you focus on line 23 and the  
10 language that is quoted -- I'm sorry, could you focus  
11 on line 23 of that? That's the language that's quoted  
12 in your report. Is that right?

13 A. Okay.

14 Q. Now, the reference to block size there is a  
15 reference to a part of a request packet. Is that  
16 right?

17 A. I don't see the reference to a request packet.

18 Q. Okay. Could you turn to page 21 of the PCT,  
19 which is page 23 of the exhibit, and look at the  
20 paragraph that starts on line 21?

21 A. Okay, I'm on page 21.

22 Q. And you're looking at line 21, the paragraph  
23 that starts on line 21? Are you there?

24 A. There's no paragraph that starts there. It  
25 looks different. My 21 looks different from the one on



1 the screen.

2 MR. DAVIS: May I approach?

3 JUDGE McGUIRE: Go ahead.

4 THE WITNESS: What page?

5 BY MR. DAVIS:

6 Q. Twenty-one.

7 A. Ah, thank you.

8 Q. There you are.

9 A. There we go. Thank you for your help.

10 Q. Now, the first sentence of that paragraph  
11 states, "In a preferred implementation of this  
12 invention shown in Figure 4, a request packet contains  
13 6 bytes of data -- 4.5 address bytes and 1.5 control  
14 bytes."

15 Do you see that?

16 A. Yes.

17 Q. And then the paragraph continues onto the next  
18 page, correct?

19 A. Yes.

20 Q. Why don't you turn to the next page.

21 A. Okay.

22 Q. So, if you look at the last sentence of that  
23 same paragraph, it states that, "The last byte contains  
24 address valid --" I'm sorry, "AddrValid (the  
25 invalidation switch) and the remaining address bits,

1 address (36:39), and block size (0:3)," then it says  
2 "control information" in parentheses.

3 Do you see that?

4 A. Yes.

5 Q. Does that indicate to you that block size is  
6 part of a request packet in the language that you  
7 quoted?

8 A. In this description, it could very well be.

9 Q. Could you turn to page 129 of the exhibit?

10 A. Page 129?

11 Q. This is the patent application. Are you on  
12 page 129?

13 A. Yes, I am.

14 Q. You see a diagram at the top labeled Figure 4,  
15 correct?

16 A. Yes.

17 Q. At the bottom of that figure, you see block  
18 size 0:3. Do you see that?

19 A. Yes, I do.

20 Q. Now, is Figure 4 the diagram in the PCT  
21 application that you believe looks like the diagram in  
22 the JEDEC standard?

23 A. Not at all.

24 Q. Could you leaf through that -- and if you look  
25 at the last pages of the PCT application, you'll see



1           JUDGE McGUIRE: Well, then, I'm unclear then as  
2 to what -- if the question is inaccurate regarding your  
3 prior testimony, then what other diagram had you  
4 referred to?

5           THE WITNESS: I referred --

6           JUDGE McGUIRE: And we're assuming that this --  
7 that what he just said is true.

8           THE WITNESS: And I may have misspoken.

9           JUDGE McGUIRE: All right, that's why I'm  
10 asking you this so we can clarify it.

11          THE WITNESS: Clearly -- and I appreciate the  
12 opportunity to clarify. Clearly block size, the  
13 technical concept of block size and the technical  
14 concept of burst length to me, as an -- as an engineer,  
15 have great similarity, and I drew that conclusion.  
16 They were not the same words, but they have -- they are  
17 the same function.

18          JUDGE McGUIRE: All right, Mr. Davis.

19          BY MR. DAVIS:

20          Q. Is that because you believe they're implemented  
21 in the same way in the patent application and in the  
22 JEDEC standard?

1 that right?

2 A. They generate the same result in terms of the  
3 number of bits that get either written or read.

4 Q. Now, I asked if you believed that they're  
5 implemented in the same way in the patent application  
6 and the JEDEC standard. I'm not sure you answered the  
7 question.

8 Do you believe they're implemented in the same  
9 way in the patent application and in the JEDEC  
10 standard?

11 A. Please note, the JEDEC standard is a  
12 specification. It does not require implementation.  
13 How something gets implemented is up to the  
14 manufacturer or the designer.

15 MR. DAVIS: I move to strike, Your Honor. It's  
16 not responsive.

17 JUDGE MCGUIRE: Well, I'm not going to strike  
18 that one. I do think it does to some extent answer  
19 your question. It may not be quite the way you had  
20 hoped, but you know, I'm going to leave it in. And I'm  
21 still somewhat unclear as to what's on the table in  
22 terms of the pending question, so you may want to go  
23 back.

24 MR. DAVIS: Well, there is no pending question  
25 at this point.

1           JUDGE McGUIRE: Well, I meant the prior  
2 question. He's answered it to the extent that you  
3 weren't pleased with it, so maybe we can go back into  
4 that if you care to do so.

5           MR. DAVIS: I might after a break. I want to  
6 make sure I think it through.

7           JUDGE McGUIRE: Okay, all right.

8           BY MR. DAVIS:

9           Q. Now, let's move on to the -- to another topic  
10 here. You also testified regarding the DLL on the  
11 DRAM, that an experienced DRAM designer would find  
12 commonality between the JEDEC on-chip DLL and the  
13 on-chip DLL that you believe was disclosed in the PCT  
14 application. Is that right?

15          A. That is correct.

16          Q. Now, you have the JEDEC standard in front of  
17 you, don't you?

18          A. That's correct.

19          Q. Could you show me where in the JEDEC standard  
20 you have in front of you there's a diagram that's the  
21 same as that in the PCT application?

22          A. Again, the JEDEC standard is a specification  
23 that does not require -- define specific  
24 implementations.

25          Q. So, if you --

1 A. Excuse me, let me finish, please.

2 Q. I'm sorry.

3 A. I will -- I will look for the -- for the  
4 specific reference for you, though, if -- and maybe  
5 someone can help me. We're looking for the extended  
6 DDR mode register --

7 Q. We're looking for -- well, I'm not sure what  
8 you're looking for at this point.

9 A. To try to answer your question, you asked where  
10 in that specification. I can reference this, and I was  
11 trying to do that for you.

12 Q. Let me see if I can short-circuit it.

13 A. All right.

14 Q. There is no figure in that standard that  
15 describes any DLL circuitry. Is that right?

16 A. Again, a standard is not supposed to --

17 JUDGE MCGUIRE: Okay, you have answered that  
18 already, sir. Maybe you can just answer the question.

19 THE WITNESS: I'm sorry.

20 JUDGE MCGUIRE: Does that exist in the JEDEC  
21 standard?

22 THE WITNESS: It does not exist in the JEDEC  
23 standard.

24 JUDGE MCGUIRE: Okay, thank you.

25 BY MR. DAVIS:

1           Q. Now, in your deposition, you stated that if the  
2 block diagram and the language is the same, that would  
3 raise a serious question for an experienced DRAM  
4 designer. Is that right?

5           A. Or if -- yes, I believe that's what I said, but  
6 certainly if the language is similar or the block  
7 diagram is similar, any one of those things will raise  
8 that question for me.

9           Q. And you referred to pages 56 to 59 of the PCT  
10 as describing the DLL that's in the application. Is  
11 that right?

12           MR. DETRE: I'll object again to the use of the  
13 deposition this way. There's no --

14           JUDGE MCGUIRE: Sustained. That's not how we  
15 use depositions, Mr. Davis.

16           BY MR. DAVIS:

17           Q. Well, you believe that the -- if the block  
18 diagram and the language is the same, that would raise  
19 a serious question for an experienced DRAM designer?

20           A. My testimony is that if a block diagram or  
21 language is similar, it will raise that concern.

22           Q. Okay. And that's --

23           A. N us Rc 2 if how sam" th,"t



1 today?

2 A. That is correct.

3 Q. Could you show me where in the portion of the  
4 patent application that you believe refers to the DLL  
5 that that 1,

1           A. That's right. And that figure is referenced in  
2 the body.

3           Q. Okay, well, let's stick with 139 for a second  
4 so that I can get on the same page as you.

5           A. All right, okay.

6           Q. Were you referring to Figure 12?

7           A. I'm -- I apologize, page 135 of 139.

8           Q. You were referring to -- you said 139. You're  
9 referring to the last --

10          A. I apologize.

11          Q. That's okay, no, understandable.

12                   And you're referring to Figure 12 that's listed  
13 there. Is that right?

14          A. Yes.

15          Q. And you were going to look for the part of the  
16 patent application that references that figure for the  
17 DLL language?

18          A. That's correct, and I believe that is somewhere  
19 in the pages that I cited where the patent application  
20 discusses clock circuitry. Let's see, you will have to  
21 bear with me, because it may take a bit.

22          Q. Sure.

23          A. (Document review.) In glancing at it right  
24 now, I can't find it.

25          Q. Are you looking at pages 56 to 59 of the PCT?

1           A. I believe so. Yes. (Further document review.)  
2 I cannot find the reference right now.

3           Q. Well, perhaps after lunch --

4           A. I can take a look at it at lunch.

5           Q. -- if you find the reference to DLL, you can  
6 point that out. I'd appreciate it.

7           A. Yes.

8           Q. Now, we have Figure 12 up on the screen, and I  
9 will ask you a few questions about that. There is no  
10 mention of the DLL there on that screen, correct?

11          A. That's correct.

12          Q. Your contention is that the circuitry itself is  
13 a DLL?

14          A. Yes, I -- I would suspect a second-year  
15 engineering student, electrical engineering student  
16 would recognize this as a DLL.

17          Q. That that's a DLL?

18          A. Yes, um-hum, potentially a DLL.

19          Q. Okay. Now, this is the figure that's similar  
20 in function to the DLL that's specified in the JEDEC  
21 DDR standard?

22          A. That's described in the -- in the DDR standard.

23          Q. See, I tried to use the word "specified" so you  
24 wouldn't have a problem with it, but that's what I  
25 meant. We already established that there is no DLL

1 figure in there.

2 A. That's correct.

3 Q. Okay. And the function of the DLL in the DDR  
4 standard is that it aligns the clock that's internal to  
5 the DRAM with the system clock?

6 A. In a general sense, yes.

7 Q. And this is --

8 A. It aligns one clock with another clock -- with  
9 another clock, one signal with another clock.

10 Q. But in the DDR standard, the clock that's being  
11 aligned is the internal DRAM clock --

12 A. Yes.

13 Q. -- and that's being aligned with the system  
14 clock. Is that correct?

15 A. Yes, I believe so.

16 Q. The DLL delays the clock that's internal to the  
17 DRAM so that it lines up with the system clock?

18 A. I believe so.

19 Q. And this is the circuit that you believe aligns  
20 the -- when I say "this," I mean Figure 12 -- this is  
21 the circuit that you believe aligns the clock that's  
22 internal to the DRAM with the system clock?

23 A. No, this is a circuit that aligns one clock  
24 with another clock.

25 Q. And what clock is being aligned here with what

1 clock?

2 A. My --

3 Q. There's two clocks being aligned. What's being  
4 aligned with what in Figure 12?

5 A. Depending on the delay lines and the values in  
6 the delay lines, we can't tell from this circuitry.  
7 It's -- excuse me, from this block diagram, we cannot  
8 tell which is aligned which way.

9 Q. Okay.

10 Your Honor, this is a good breaking point for  
11 me.

12 JUDGE MCGUIRE: Okay, it's 12:30. Why don't we  
13 break for lunch and reconvene at 1:45. The hearing is  
14 in recess.

15 (Whereupon, at 12:30 p.m., a lunch recess was  
16 taken.)

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1 and then I'll give their side an opportunity to respond  
2 either in writing or orally on that regard, and we're  
3 going to have to tie this up in pretty short order.

4           Could I inquire of I guess complaint counsel,  
5 do you have some idea at this point who you intend to  
6 offer in rebuttal?

1 before they conclude their case in chief on Tuesday.

2 MR. OLIVER: That would be fine, Your Honor.  
3 If I could simply ask if there is any unexpected  
4 testimony after Thursday, would we be able to augment  
5 if necessary? I don't anticipate that, but if  
6 necessary.

7 JUDGE McGUIRE: Well, we will take that up at  
8 the time, but we'll see.

9 MR. OLIVER: Thank you, Your Honor.

10 JUDGE McGUIRE: Did you have anything else, Mr.  
11 Perry, you wanted to add to this discussion?

12 MR. PERRY: No, Your Honor.

13 JUDGE McGUIRE: Okay, good.

14 Let's go back -- sir, you can take the stand  
15 again, and you are still under oath from this morning.  
16 Thank you.

17 Mr. Davis, you can proceed with your cross  
18 examination.

19 MR. DAVIS: Thank you, Your Honor.

20 BY MR. DAVIS:

21 Q. Actually, I have a few questions, Mr. Geilhufe,  
22 on your background --

23 JUDGE McGUIRE: You know, just again, let me  
24 just say, I'm probably going to issue just a short  
25 order tomorrow, if I can, just to give you the scope of



1 what I intend to see on rebuttal just so we're clear.  
2 It's going to be a very short order, just something to  
3 give you all some guideline on where I want to see this  
4 to go, and then we can do what we said we're going to  
5 do.

6 Okay, Mr. Davis, go ahead.

7 BY MR. DAVIS:

8 Q. Do you recall this morning you testified that  
9 you had four patents in the DRAM design area?

10 A. That's correct.

11 Q. When was the last DRAM design patent issued?

12 A. I don't recall. Probably in the early  
13 eighties.

14 Q. In the early eighties? When was the one before  
15 that?

16 A. I really don't recall. It's a long time ago.

17 Q. Okay, I thought I had one more background  
18 question. Maybe I didn't.

19 Now, there was a question from this morning  
20 that you were going to look at over lunchtime, which  
21 was where in the PCT application DLLs are mentioned.  
22 Did you have a chance to look at that over lunch?

23 A. I think I stated that the PCT application  
24 referenced Figure 12 in the document itself, and you  
25 asked me to identify where that reference was.

1 Q. No, I asked you to identify where DLLs were  
2 mentioned in the patent application.

3 MR. DETRE: I think that misstates Mr.  
4 Geilhufe's prior testimony. He never said DLLs were  
5 specifically mentioned. He said there was a reference  
6 to Figure 12 that shows a DLL.

7 MR. DAVIS: I wasn't actually referencing, Your  
8 Honor, any prior testimony. I was referencing my prior  
9 question to Mr. Geilhufe, which was where DLL was  
10 mentioned --

11 JUDGE MCGUIRE: I'll entertain the question.

12 BY MR. DAVIS:

13 Q. Did you have a chance to look for the mention  
14 of DLLs in the patent application over lunch?

15 A. It is not mentioned in the patent  
16 application --

17 Q. Okay.

18 A. -- that particular word, just a DLL circuit is  
19 in the patent application.

20 Q. And that's Figure 12?

21 A. That is correct.

22 Q. Now, I would like to ask a few questions about  
23 the tables that you presented this morning. As  
24 introduction, I'll have some clarification questions,  
25 and let me make sure I find the right one.

1           Are you able to see the screen -- actually, you  
2 probably have your own copy of that.

3           Actually, yeah, I don't have an electronic copy  
4 of this. Would you -- is it possible for you to put  
5 this up --

6           MR. DETRE: Sure, if you could change -- switch  
7 over the computer to that.

8           MR. DAVIS: To counsel computer?

9           MR. DETRE: Yeah. DX-298, is that --

10          MR. DAVIS: Is that the CAS latency?

11          MR. DETRE: Yes, DX-298.

12          MR. DAVIS: Great.

13          BY MR. DAVIS:

14          Q. Now, if you look at the CAS latency -- let me  
15 see -- I'm sorry, it's DX-299 that I have. That's the  
16 effect of the burst length alternatives.

17          A. Yes.

18          Q. Look under Burst Length in Read/Write Command,  
19 under the Estimated Cost Increase or Decrease, it says  
20 0.005 cents to 0.2 cents?

21          A. That's correct.

22          Q. Are you saying there's a half a cent to a 20  
23 cent increase in price per unit?

24          A. No, it's 2 cents. I see it's a typo. I  
25 apologize for that. It should be 0.02. Thank you for

1 correcting it.

2 Q. All right. Now, when you presented your  
3 testimony today regarding the DRAM costs, what you were  
4 presenting wasn't actual DRAM costs but a model of DRAM  
5 costs based on your experience?

6 A. As I testified, I modeled these alternatives,  
7 that is correct.

8 Q. Okay. As a result of the fact that you were  
9 using a model, all of the information presented in your  
10 testimony was approximate?

11 A. That is -- that is correct. All the  
12 information is estimated.

13 Q. In fact, you believe that the margin of error  
14 for each of the cost elements described in your  
15 presentation is 25 percent. Is that right?

16 A. At -- at worst. I suspect it's less than 25  
17 percent.

18 Q. And you base that margin of error on your  
19 experience?

20 A. Yes, as I made many -- more and more and more  
21 cost estimates over my career, they tended to get  
22 better.

23 Q. And you didn't test your projections in this  
24 case to any actual results to see if the results  
25 actually were within 25 percent of the actual numbers,

1 did you?

2 A. Well, since the vast majority of these never  
3 got implemented, it was not possible to test them.

4 Q. So, the answer is no, you didn't test?

5 A. I did not.

6 Q. And the only way that you can think of for  
7 anyone else to verify or validate the cost numbers that  
8 you arrived at is to ask a DRAM manufacturer,  
9 particularly a firm like Infineon?

10 A. I know I stated something to that effect in my  
11 deposition. I need to clarify that comment. Since it  
12 never got implemented, many of these alternates never  
13 got implemented at a DRAM manufacturer, it would be  
14 impossible for a DRAM manufacturer to verify many of  
15 these alternatives.

16 Q. But to the extent that they were implemented in  
17 some fashion, that would be how I would validate them?

18 A. That would be one possible way, if they were  
19 indeed implemented.

20 Q. And you never did that; you never attempted to  
21 verify the numbers you came up with with the DRAM  
22 manufacturers.

23 A. Mr. Davis, please recognize, cost information  
24 is the most carefully held, confidential information in  
25 the corporation and is not available to someone who's

1 not in the corporation.

2 Q. You didn't ask Rambus to conduct discovery on  
3 that question, did you?

4 A. I did not.

5 Q. And you didn't actually review any documents  
6 relating to the manufacturing costs of DRAM  
7 manufacturers in this period?

8 A. I -- there are a series of estimates by  
9 industry analysts that suggest my cost numbers,  
10 certainly the total cost numbers, seem to be correct.  
11 I did over the years review and I'm aware of what  
12 analysts said about costs.

13 Q. Were those estimates by industry analysts  
14 included in the documents you relied on, you attached  
15 to Exhibit B to your report?

16 A. No, they were not.

17 Q. Now, since the numbers that you gave us are  
18 based on your own experience, you can't speak for any  
19 of the DRAM manufacturers in the relevant time period  
20 in terms of what their costs actually were, can you?

21 A. Clearly -- as I stated, cost information is  
22 highly confidential, and I cannot speak for the actual  
23 costs at a DRAM manufacturer. I can only speak for the  
24 model that I feel is a credible model that I used.

25 Q. You did read a deposition of an employee of a

1 current DRAM manufacturer regarding what the -- what he  
2 thought the actual DRAM manufacturing costs would be,  
3 didn't you?

4 A. I -- can you be more specific? I'm -- it's too  
5 general.

6 Q. You read the deposition of Dr. Peisl, didn't  
7 you?

8 A. Yes, I did.

9 Q. And Dr. Peisl's a current employee of Infineon,  
10 correct?

11 A. I believe so.

12 Q. And you might recall that Dr. Peisl either  
13 designed or managed the design -- design team for a  
14 number of DRAMs. Do you remember reading that?

15 A. I understand that, yes.

16 Q. Dr. Peisl was involved in the design of EDO in  
17 1994. Do you remember reading that?

18 A. Right, I recall that.

19 Q. And Dr. Peisl managed a team designing the SDR  
20 and DDR combination part that Infineon made?

21 A. I recall that.

22 Q. I think they called it Cronus, do you remember  
23 that name?

24 A. Something to that effect.

25 Q. And Dr. Peisl also managed the design of the

1 256-megabit DDR SDRAM part called Orion. Do you recall  
2 that?

3 A. Correct. He testified to that as I recall.

4 Q. So, Dr. Peisl was either designing DRAMs or  
5 managing the design of DRAMs during the relevant  
6 period, to your understanding?

7 A. To my understanding.

8 Q. And in the deposition that you read by Dr.  
9 Peisl, he talked about what he believed to be the cost  
10 impact of some of the alternatives based on his own  
11 DRAM design experience. Do you remember reading that?

12 A. I don't recall the specifics. Maybe you can  
13 refresh my memory.

14 Q. I think I will in due course.

15 Dr. Peisl also testified that there's an entire  
16 organization at Infineon that does an analysis of the  
17 cost of manufacturing DRAM. Do you remember reading  
18 that?

19 A. I recall something to that effect. It's very  
20 common in DRAM manufacturing organizations.

21 Q. Dr. Peisl himself could only take an educated  
22 guess at the actual cost of alternatives but only after  
23 reviewing a million Excel spreadsheets?

24 A. I don't remember reading that exact comment,  
25 but if you can read it for me.



1 Q. Okay. The Peisl deposition?

2 May I approach, Your Honor?

3 JUDGE McGUIRE: Go ahead.

4 MR. DETRE: Your Honor, this is not a proper  
5 use of the deposition testimony of Dr. Peisl. This is  
6 not evidence that's in the record here at this trial.  
7 Dr. Peisl testified at trial. I don't think it's  
8 appropriate to try to get his deposition testimony in  
9 in this manner.

10 MR. DAVIS: I'm not trying to get the  
11 deposition testimony in at all. Dr. -- I'm sorry, Mr.  
12 Geilhufe read this testimony. It was part of the  
13 information that he reviewed prior to his deposition at  
14 least, and the question is how did the use of this  
15 information affect his opinions?

16 JUDGE McGUIRE: I will hear it on that basis.

17 BY MR. DAVIS:

18 Q. Now, if you turn to page 193, starting at line  
19 20, and I'll read the lines and then ask you if that  
20 comports with your reading.

21 "QUESTION: You asked me the question as to did  
22 or could -- could you provide a total cost estimate for  
23 these two alternatives?

24 "MR. WILKINS: Right now he is just asking yes  
25 or no.

1 "THE WITNESS: Yes."

2 "QUESTION: Okay. Could you do that sitting  
3 here?

4 "ANSWER: No.

5 "QUESTION: What would you have to do to make  
6 that cost estimate?

7 "ANSWER: To go through a million Excel files.

8 "QUESTION: To go through a million Excel  
9 files?

10 "ANSWER: Excel files."

11 Then he goes on to describe what he means by  
12 that.

13 Do you remember reading that?

14 A. I just read it again. I now recall reading it.

15 Q. But that didn't make you think that you needed  
16 to get more data before deciding what the cost of the  
17 alternatives would be, did it?

18 A. Well, it suggests the answer that Mr. Peisl  
19 gave was a somewhat incredulous answer. No one reads a  
20 million Excel files, at least not a human being that I  
21 know of.

22 Q. You didn't take his answer to mean that it  
23 would require a lot of work to --

24 A. I took it literally.

25 Q. Let me finish my question.

1 A. Certainly.

2 Q. You didn't take his answer to mean that it  
3 would require a lot of work to come up with the actual  
4 cost estimates?

5 A. I took his answer as a nonanswer. Anyone who  
6 suggests the reading of a million Excel files suggests  
7 something that's incredulous.

8 Q. So, the next question and answer states:

9 "QUESTION: What do you mean by that?

10 "ANSWER: My company in Munich, this is done by  
11 people in headquarters, has very accurate cost  
12 estimation --"

13 A. Excuse me, would you tell me what line, please,  
14 again?

15 Q. Starting on line 9.

16 A. Page?

17 Q. Page 194, just continuing.

18 A. One minute.

19 Q. "ANSWER: My company in Munich, this is done by  
20 people in headquarters, has very accurate cost  
21 estimations and cost projections of essentially  
22 whatever it takes to produce a manufacturer test, so I  
23 would have it to look at this in detail to come up with  
24 an educated guess."

25 Does that still make you think that he was

1       stating that -- that he was giving a nonanswer?

2           A.   If an executive in a billion dollar business  
3 gives these kinds of answers, it suggests that he  
4 really doesn't understand what he's answering or that  
5 he really doesn't know an answer.  This is -- you know,  
6 if someone gave me that answer when I -- if I would  
7 have asked the question during a business review, that  
8 individual would go back to work and get much, much  
9 better answers.

10          Q.   And Dr. Peisl himself was unwilling to give any  
11 specific numbers for the costs of alternatives without  
12 doing the actual circuit designs that were required to  
13 determine what was being estimated.  Do you recall  
14 reading that?

15          A.   I think that is a much, much more appropriate  
16 answer.

17          Q.   You didn't do any circuit design for this case,  
18 did you?

19          A.   Since the alternatives that I was asked to look  
20 at did not include circuit design, that suggests  
21 already that they were poorly thought out alternatives.  
22 They were not detailed enough to do any circuit design.  
23 If the alternatives that Dr. Jacob had offered included  
24 circuit design, we would have been able to -- I would  
25 have been able to do that analysis, of course.

1 Q. But you didn't do any circuit design in this  
2 case, did you?

3 A. I could not do any circuit design.

4 Q. So, you didn't?

5 A. I did not.

6 Q. Now, you're not offering an opinion in this  
7 matter that the method that you followed in this case  
8 is the same method used by JEDEC representatives,  
9 right?

10 A. I am only offering the -- my model as my  
11 method, as a method that has been proven over a long  
12 period of time to be reasonably successful.

13 JUDGE MCGUIRE: Well, I'm not sure that answers  
14 his question. It either did comport with what the  
15 JEDEC --

16 THE WITNESS: I have no --

17 JUDGE MCGUIRE: And if you don't know, you  
18 don't know.

19 THE WITNESS: I have no knowledge of how JEDEC  
20 folks did their analysis or if they did an analysis,  
21 Your Honor.

22 BY MR. DAVIS:

23 Q. Now, you stated earlier today that each of the  
24 alternatives that you reviewed could have been  
25 implemented in a six to twelve-month time frame. Is

1 that accurate?

2 A. It is my belief that that could happen.

3 Q. But in making that determination, you didn't  
4 include any consideration of how long it would take  
5 JEDEC to determine which alternatives to put in the  
6 standard, did you?

7 A. Of course not. That wasn't -- just not.

8 Q. And your determination of six to twelve months  
9 was based on your own experience?

10 A. It's based on the industry experience of how  
11 often a DRAM normally gets revised during its  
12 manufacturing cycle. So, it would literally -- I  
13 estimated that this would be a piggyback on existing  
14 revisions that were going on.

15 Q. But how long would it take to actually do the  
16 design and implement those designs, you thought that  
17 would take six to twelve months from when one decided  
18 to do it, right?

19 A. That is correct.

20 Q. So, that part of the question, you thought it  
21 would take six to twelve months to implement these  
22 standards which was based in part on your industry --  
23 your own experience of how long it would take to  
24 implement those?

25 A. That's correct.

1           Q.  And you didn't review any evidence that might  
2 tell you how long it would take to change the DRAM  
3 designs?

4           A.  I certainly understand how long it takes or has  
5 taken at Winbond recently.  I certainly understand or  
6 one can interpolate from Samsung's product codes, which  
7 identify the revision codes in the product code,  
8 approximately how often they change their redesign or  
9 change their product.

10          Q.  But I'm asking you how long it would take a  
11 DRAM designer to do the design, not how often they  
12 revise the designs.

13          A.  Excuse me, that's not the question you asked  
14 before.  You asked design and implement.  If we're just  
15 talking about design, that's a different issue.

16          Q.  Okay.  You didn't review any evidence that  
17 might tell you how long it would take to design -- I'm  
18 so 18    17 ntMw metMwom

1 and 2000?

2 A. Yes. Recall, ISD and Winbond were partners  
3 before that, and then I became part of Winbond.

4 Q. And this was when you had testified that you  
5 didn't have any DRAM manufacturing -- let me get back  
6 to the actual testimony that you gave.

7 Now, this is where you said that your  
8 manufacturing experience was limited to being aware of  
9 the volumes and types of DRAMs that were being  
10 manufactured and the profitability of the DRAMs?

11 A. Right, so I was aware of the revisions of the  
12 DRAMs.

13 JUDGE MCGUIRE: Let him finish, and then I'll  
14 ask you to file your objection. Go ahead.

15 MR. DETRE: When --

16 JUDGE MCGUIRE: No, I am going to let him  
17 answer the question.

18 Well, if you don't remember it, now, what's  
19 your objection?

20 MR. DETRE: I don't -- Mr. Davis said "you  
21 said." I don't know if he's looking at trial testimony  
22 or deposition testimony or what. If it's the latter,  
23 he hasn't properly impeached the witness with it.

24 JUDGE MCGUIRE: Could you clarify, Mr. Davis?

25 MR. DAVIS: I just reread a question that I had



1 read this morning that he answered "yes" to.

2 JUDGE McGUIRE: Does that satisfy you, Mr.  
3 Detre?

4 MR. DETRE: I'm not sure if Mr. Davis is  
5 characterizing the record correctly or not, frankly.  
6 He's citing his own notes apparently.

7 JUDGE McGUIRE: I am going to assume that he  
8 has, and if he hasn't, n't, frankly.

ks is "i teufceT\*o has, and if he ha9e haback inT\*t onot,di.  
11 I'm not suBYure ifAVIS: Detre?  
1UIRE: DoQ. Lets ago through so ofor nocost elem s k Detre?  
1 discusse answered "yes Detre?



1           A. And my experience in -- in many other products  
2 that I've done over my career.

3           Q. You reviewed no evidence relating -- in this  
4 case relating to the costs of DRAM manufacturers for  
5 this element from the relevant period other than the  
6 Peisl deposition. Is that right?

7           A. That's correct, and the Peisl deposition  
8 suggests my numbers seem to make sense.

9           Q. So, your recollection from reading the Peisl  
10 deposition was that he agreed with your design costs?

11          A. He suggested the size of the design teams that  
12 were required were consistent with what my  
13 understanding of the industry is.

14          Q. Well, I'd like to focus your attention on the  
15 Peisl deposition, in particular --

16                 Did I give you a copy of that, Your Honor?

17                 JUDGE MCGUIRE: No, I don't -- well, I'm sorry,  
18 which one is that?

19                 MR. DAVIS: That's the Peisl deposition.

20                 JUDGE MCGUIRE: No, I've just got his  
21 deposition.

22                 MR. DAVIS: May I approach?

23                 JUDGE MCGUIRE: Yes.

24                 MR. DAVIS: I had an extra copy and I wasn't  
25 sure why. Sorry.

1 BY MR. DAVIS:

2 Q. If you would turn to page 74 and focus in  
3 particular on line 15, and I'll read it and ask you if  
4 I'm reading it correctly.

5 "QUESTION: Okay, well, let's go through them.  
6 What do you understand product design to be?

7 "ANSWER: Product design is the cost involved  
8 for engineers for designing of parts.

9 "QUESTION: Would designing fixed CAS latency  
10 parts be more expensive than designing a part that had  
11 programmable latency?

12 "ANSWER: No."

13 Do you recall reading that?

14 A. Yes.

15 MR. DETRE: Objection, Your Honor. Again, we  
16 object to getting the Peisl deposition testimony into  
17 evidence, if that's what Mr. Davis is attempting to do.

18 MR. DAVIS: I'm not. I'm asking what the  
19 effect of that -- of reading that portion of the  
20 deposition had on his opinion that there would be  
21 higher design costs.

22 JUDGE MCGUIRE: I indicated earlier that on  
23 those grounds, I would hear the question, and it's  
24 going to be to that extent only.

25 MR. DETRE: Thank you, Your Honor.

1           MR. DAVIS: And in fact, I can stipulate that  
2 any time I read from the Peisl deposition, it's solely  
3 for that purpose.

4           JUDGE McGUIRE: Okay, thank you, Mr. Davis.

5           MR. DETRE: Thank you.

6           BY MR. DAVIS:

7           Q. Dr. Peisl thought that the design of -- that --  
8 I'm sorry.

9                    Did Peisl thought that the design of the  
10 alternative that we were discussing in that deposition,  
11 which is fixed CAS latency, was less expensive than  
12 what was in the current standard. Is that right?

13           A. Would you read that for me? I don't see that.

14           Q. I'm sorry, he said that designing the fixed CAS  
15 latency wouldn't be more expensive than programmable  
16 CAS latency, correct?

17           A. That's what he states here, and of course, he's  
18 wrong, as he knows himself. If you want to do another  
19 product, it takes a design cycle. If you --

20           Q. But he's not talking about doing another  
21 product, is he? You were -- your estimates were of  
22 doing a product instead of doing the JEDEC standard  
23 product. Isn't that right?

24           A. My estimates are of doing several products  
25 instead of the JEDEC product.

1 Q. Well --

2 A. And I estimated a cost for each one of those.

3 Q. So, then, did you deduct the cost of doing the  
4 JEDEC standard product from your estimate of doing the  
5 fixed CAS latency?

6 A. Of course, the design of the base product is a  
7 \$10-\$20 million effort. To do this derivative -- for  
8 instance, the first design of a 256-meg product is a  
9 very, very expensive effort. So, to do these  
10 derivative products is only a small design effort.

11 Q. No, I asked you, did you deduct the cost of  
12 doing the JEDEC standard product from your estimates  
13 for fixed CAS latency?

14 A. And I just answered it. If I had not deducted  
15 it, the cost would be \$10 or \$15 million.

16 Q. Okay, let me focus your attention on page 138.

17 MR. DETRE: Of Peisl's deposition?

18 MR. DAVIS: Yes, I'm sorry.

19 BY MR. DAVIS:

20 Q. Now, I'll focus your attention on the question  
21 starting on line 6.

22 "QUESTION: If you look at Table 2, which is  
23 Exhibit 2, you look at the first column, which  
24 discusses fixed burst length rather than programmable  
25 burst length, okay?"

1           Then I am going to skip the parenthetical.

2           "QUESTION: Looking at the costs that are  
3 listed in this column as well as the total costs, are  
4 there costs in there that you would agree with or  
5 disagree with?"

6           There are some objections, and the witness  
7 answers:

8           "ANSWER: I would disagree with the same issues  
9 I mentioned before. The product design is no add-on,"  
10 and there's a number of others.

11           Dr. Peisl disagreed with you on every  
12 alternative for design costs, didn't he?

13           A. I don't know that.

14           Q. You don't recall?

15           A. I don't know that. You just specified --  
16 specifically talked about a burst length design  
17 alternative here.

18           Q. Now, Dr. Peisl supervised design teams  
19 designing the 256-megabit SDRAM and DDR SDRAM parts in  
20 the mid-1990s. Do you remember reading that in his  
21 deposition?

22           MR. DETRE: Objection, Your Honor. There is no  
23 foundation for the --

24           JUDGE MCGUIRE: Sustained.

25           MR. DAVIS: Mr. Geilhufe already stated that he

1 understood that from the deposition. I was just  
2 establishing a foundation for the next question.

3 JUDGE McGUIRE: Well, I don't know. I don't  
4 know what he said. I've sustained the objection.

5 BY MR. DAVIS:

6 Q. Now, part of Dr. Peisl's job had been to  
7 estimate the design costs for the DRAMs. Do you recall  
8 reading that?

9 MR. DETRE: Objection, Your Honor. Mr.  
10 Geilhufe has no foundation to say what Dr. Peisl's job  
11 was or wasn't.

12 MR. DAVIS: I'm asking if he recalls reading  
13 that in his deposition, not if he knows Dr. Peisl's  
14 job.

15 JUDGE McGUIRE: I will hear it on that very  
16 tight basis, then.

17 THE WITNESS: I do not -- it's a large  
18 document. I do not recall reading that.

19 BY MR. DAVIS:

20 Q. Let me direct your attention to page 41 and  
21 line 22.

22 "QUESTION: During your --" and I'm reading  
23 from line 22 on page 41.

24 A. Um-hum.

25 Q. "QUESTION: During your tenure at Infineon,



1 have you had to make estimates of manufacturing costs  
2 for any products that you were involved in?

3 "ANSWER: I did once estimate for design  
4 effort, meaning we had head count, for the 16-megabit

1 A. Just like I did.

2 Q. -- and that's what he did as part of his job as  
3 well?

4 A. That's what he says, and it's interesting, only  
5 for one product. I find that a very unusual statement.

6 Q. Actually, he said that for a number of  
7 products.

8 A. Oh, good.

9 Q. But you didn't see a need -- I mean, you and  
10 Dr. Peisl disagreed on what the design costs were,  
11 didn't you?

12 A. I don't know what Dr. Peisl estimated for a  
13 design cost for what element.

14 Q. Well, we can go through all the other ones I  
15 guess. So, we did fixed CAS latency and fixed burst  
16 length. We read Dr. Peisl's testimony on those two,  
17 correct? Just a few minutes ago.

18 A. We only read it for one alternative, I believe.

19 Q. No, we read it for two. Let me try it again.  
20 If you go to 74, page 74, line 15.

21 A. Um-hum.

22 Q. He's talking about the design costs for a fixed  
23 CAS latency part, correct?

24 A. Correct.

25 Q. If you go to page 138, line 6, he's talking

1 about a fixed burst length part?

2 A. Right.

3 Q. Well, let's go to page 105, line 2. Are you  
4 there?

5 A. Bear with me, I apologize. There we go.

6 Q. "Would designing --" I'm sorry, "Would using --  
7 would designing a product with electrical fuses add to  
8 your design costs versus just using laser-blown fuses?

9 "ANSWER: No."

10 So, there's another example where Peisl  
11 disagrees with --

12 A. That's now a third example, yes, we now have  
13 three.

14 Q. Would you go to page 159?

15 A. Yes.

16 Q. Starting at line 22:

17 "QUESTION: Do you have any idea based on your  
18 experience how much it would cost to double the data  
19 width on an SDRAM in 1998?"

20 There were some objections.

21 "ANSWER: If I go through the rows again for  
22 the product design, I would maintain that there was  
23 zero add-on. With a good die yield, I would agree that  
24 there was some critical die area," and I could keep on  
25 reading, but we're talking about design.

1           So, that's another area where he disagreed with  
2 you on the DRAM design?

3           A. That's correct. That's his testimony.

4           Q. If you would go to page 154, starting on line  
5 9, "If you look at the first column in Exhibit 3,  
6 there's a number of costs -- a number of costs for  
7 implementing that particular alternative. Assuming  
8 costs in the mid-1990s of volume product, and that  
9 alternative was implemented for SDRAM at the time the  
10 JEDEC specification was set, do you have an opinion one  
11 way or the other as to whether these cost increases are  
12 accurate?

13                   "ANSWER: Based on my experience, the product  
14 design add-on would be zero."

15           Now, for that alternative, if you turn to the  
16 previous page, 153, you'll see that he's talking about  
17 interleaving on chip memory banks.

18           A. Excuse me?

19           Q. If you turn to page 153 --

20           A. Yes.

21           Q. -- at the very bottom --

22           A. Um-hum.

23           Q. -- he says, "Had you --" you can see that the  
24 question was related to on-chip memory banks and using  
25 two blocks as an alternative to dual edge clocking

1 technology.

2 A. Oh, that is a very surprising statement for  
3 someone knowledgeable in design. If you're adding a  
4 clock, you better do some design.

5 Q. So, he disagreed with your -- with your  
6 conclusions, so you're just saying that he's wrong. Is  
7 that right?

8 A. I disagree with his conclusions.

9 Q. Now, you don't have any -- excuse me.

10 Now, we were talking about fixed CAS latency  
11 and fixed burst length a minute ago. You don't have  
12 any negative figures for the design costs for any of  
13 the alternatives, correct?

14 A. That is correct.

15 Q. That means you thought that none of the  
16 alternatives that were proposed by Professor Jacob were  
17 cheaper to design than the alternatives in the JEDEC  
18 standard?

19 A. That was my estimate, yes.

20 Q. And you thought that fixed CAS latency and  
21 fixed burst length was more expensive to design than  
22 programmable CAS latency and burst length?

23 A. Because there were different parts that needed  
24 to be aligned, it is more expensive in total.

25 Q. At the time you reached your conclusions, were

1 you aware that the proponents of SDRAM-Lite at JEDEC  
2 were thinking of using a fixed CAS latency of three as  
3 late as January of 1996?

4 A. That's outside the scope of my analysis. I --  
5 I don't see what bearing that has on my cost analysis.

6 Q. Were you aware that the JEDEC members  
7 themselves believed that eliminating the ability to set  
8 the latency and burst length would reduce design costs?

9 A. Please --

10 MR. DETRE: Objection, Your Honor, misstates  
11 the record.

12 BY MR. DAVIS:

13 Q. Are you aware that -- withdrawn.

14 JUDGE MCGUIRE: Well, sustained.

15 BY MR. DAVIS:

16 Q. Are you aware that Terry Lee testified based on  
17 his understanding at the time that the use of fixed CAS  
18 latency and fixed burst length would reduce design  
19 costs?

20 A. I am not aware of that.

21 MR. DAVIS: One second, please.

22 (Counsel conferring.)

23 JUDGE MCGUIRE: And Mr. Davis, I'm having --  
24 there's often times during this hearing I have trouble  
25 hearing people that aren't right up to the podium or at

1 their table, so you tend to go back and forth, which is  
2 okay, but just make sure that I hear you when you do  
3 so.

4 MR. DAVIS: Yes, Your Honor. Unfortunately, I  
5 had caffeine this morning or this afternoon, so it  
6 makes me move around too much.

7 JUDGE McGUIRE: All right.

8 BY MR. DAVIS:

9 Q. Now, looking at the product design costs for  
10 the use of the burst terminate command, you thought  
11 that was a fairly complex design change from the  
12 current standard? If you want to refer to your tables,  
13 that might refresh your recollection.

14 A. Thank you. (Document review.) Yes, I felt it  
15 was somewhat more complex than a simple design change,  
16 like implementing fuses.

17 Q. Did you make any assumptions about the burst  
18 length that would be required for use for the burst  
19 terminate -- if there was a burst terminate command?  
20 For example, did you assume -- let me withdraw that  
21 question and ask another one.

22 Did you assume that the burst terminate command  
23 would be required to accommodate a burst interrupt of  
24 one?

25 A. Of course. If you don't have a burst length

1 register, you would have to interrupt a single data  
2 bit, which, of course, is not possible.

3 Q. And you thought that there would be required to  
4 be a burst interrupt to interrupt the burst at a one  
5 because it was in the current JEDEC standard?

6 A. A -- it is a requirement for any DRAM to be  
7 able to output a single bit at a time.

8 Q. I'd like to turn to wafer sort. Now, this  
9 element depends on the amount of test time required to  
10 test the alternative over the time required to test the  
11 current standard. Is that right?

12 A. That is correct.

13 Q. And your basis -- I'm sorry, the basis for your  
14 opinions for this element was your experience in the  
15 DRAM industry?

16 A. It's -- it's my experience in wafer sort  
17 testing for DRAMs and for flash memories, for SRAMs and



1 Q. You say you were aware. When were you aware?

2 A. At this time frame.

3 Q. And that was because of work that you did with  
4 the DRAM manufacturers?

5 A. That is correct.

6 Q. And that was work that you did with the DRAM  
7 manufacturers that I asked you about at your  
8 deposition? Do you remember that?

9 A. I don't remember which DRAM manufacturers you  
10 asked me about.

11 Q. Well, I -- can I have the deposition? Oh, I  
12 have it.

13 Is this confidential information, Mr. Geilhufe?

14 A. Of course.

15 Q. It is confidential information?

16 A. Yes.

17 Q. So, when I asked you about it -- if I had asked  
18 you about it at the deposition, you wouldn't have told  
19 me what those would have been, would you?

20 A. No.

21 Q. I couldn't have found out what those numbers  
22 were from you?

23 A. It is confidential information that I obtained  
24 under confidentiality agreements which I'm bound by.

25 Q. But other than the confidential information

1 that I wasn't able to get information about from you,  
2 you reviewed no evidence in this case about this cost  
3 element?

4 A. Well, actual data is pretty solid information.  
5 So, beyond the actual data, I did not review anything  
6 else.

7 Q. When you read the deposition of Dr. Peisl, he  
8 thought that in order to come up with a number for the  
9 test costs, you'd have to write up a set of test  
10 programs to see for sure whether there would be any  
11 change in test costs. Do you recall reading that?

12 A. I don't recall reading that.

13 Q. If I could refer you to page 77, line 9.

14 "QUESTION: Okay, wafer sort, what do you  
15 understand that to be?

16 "ANSWER: Wafer sort is the sorting of good  
17 dies -- sorting out the good dies from the bad dies of  
18 the wafer according to the test program.

19 "QUESTION: Do you see here that it says using  
20 fixed CAS latency parts would decrease your test time?

21 "ANSWER: This is what I believe I said five  
22 minutes ago, no.

23 "QUESTION: So, you don't believe there would  
24 be any decreased test time for using fixed CAS latency  
25 parts --" I'm sorry, it doesn't say fixed, but --

1           "ANSWER: I have not written a test program in  
2 order to assess the differences quantitatively. My  
3 feeling would be that it would be absolutely close to  
4 zero, because from my experience, tests like CAS  
5 latency are built into other tests in parallel. We  
6 usually test two or three things in parallel with the  
7 same test. So, just waiving this particular CAS  
8 latency test would not necessarily change the duration  
9 of the test program."

10           Do you remember reading that?

11           A. I -- I recall -- I see it reading it now.

12           Q. You didn't write up any test programs to see  
13 whether changing the test time at wafer sort would  
14 change for any of the alternatives, did you?

15           A. No, I did not write any test program.

16           Q. I'd like to turn to good die yield. Now, to  
17 figure out the effect on good die yield of some of the  
18 alternatives that you analyzed, you knew that you had  
19 to look at some of the changes in circuitry that would  
20 be required to implement the alternative as compared to  
21 the current standard, correct?

22           A. I had to make some very rough estimates at  
23 that, yes.

24           Q. But as you testified earlier, you never  
25 actually did a detailed design of the circuitry that

1 would be required to implement it.

2 A. That's correct, there was no circuit design and  
3 no layout done.

4 Q. And you never really looked at the circuitry  
5 that you could remove from the DRAM after omitting the  
6 standard feature, did you?

7 A. I estimated if some circuitry could be removed  
8 or some circuitry had to be added.

9 Q. But you never really looked at the circuitry  
10 that you could remove, specific circuitry, did you?

11 A. Of course. For instance, for the DLL option, I  
12 looked at the -- removing the DLL from the -- from the  
13 chip.

14 Q. Did you look at removing the circuitry for the  
15 dual edged clocking alternative?

16 A. I did not.

17 Q. Once you made the determination that the  
18 circuit size would be larger for the alternative than  
19 for the original, you assumed that the increase in  
20 circuit size would lead to a reduction in yield?

21 A. Yes, I did.

22 Q. And in making this determination, you were  
23 estimating that what you generally believed to be --  
24 what you -- I'm sorry, strike that.

25 In making this determination, you're estimating



1 Peisl's testimony. We would have to go element by  
2 element by element.

3 Q. Do you recall Dr. Peisl disagreeing with your  
4 estimates of changes in good die yield for any of the  
5 alternatives?

6 A. Say that again, please.

7 Q. Do you recall Dr. Peisl disagreeing with your  
8 estimates for changes in the good die yield for any of  
9 the alternatives?

10 A. Not specifically, no, I do not.

11 MR. DETRE: Your Honor, I'm going to object on  
12 relevance grounds. We've heard so much from Dr.  
13 Peisl's deposition at this point. Mr. Geilhufe has his  
14 opinion, and apparently Dr. Peisl had a different one  
15 in his deposition. I'm not sure what the relevance is  
16 of reading all these in.

17 MR. DAVIS: Again, the relevance --

18 JUDGE MCGUIRE: Mr. Davis, I will give you a  
19 chance to respond to that.

20 MR. DAVIS: The relevance is that Dr. -- Mr.  
21 Geilhufe read Dr. Peisl's deposition prior to  
22 testifying here today and giving his opinion. Dr.  
23 Peisl is a current practitioner in this same area that  
24 Mr. Geilhufe --

25 JUDGE MCGUIRE: Well, so ultimately you're

1 showing that they don't agree, so they don't agree, and  
2 that's in the record. Maybe you could expedite this  
3 and ask him if there are some areas in the Peisl  
4 testimony that he does disagree with and not have to go  
5 through each and every one of them.

6 MR. DAVIS: I tried that, Your Honor, and --

7 JUDGE McGUIRE: It is not aiding this Court to  
8 understand that they disagree.

9 MR. DAVIS: The purpose of the cross isn't to  
10 show that they disagree, but it's to show that Mr.  
11 Geilhufe saw that there was another person who  
12 disagreed with him and he didn't do anything to check  
13 his estimates, even though he only based them on his  
14 experience.

15 MR. DETRE: I think Mr. Davis has now  
16 established that at least half a dozen times. He could  
17 ask one question and ask after reviewing the Peisl  
18 deposition, did you do any further work based on it,  
19 and we could be done with it.

20 JUDGE McGUIRE: Okay, that's what I'm going to  
21 suggest we do at this point, Mr. Davis. We can  
22 expedite this if we can clarify your inquiry.

23 MR. DAVIS: Let me just see the question that  
24 Mr. Detre asked.

25 BY MR. DAVIS:

1 Q. Now, after seeing the -- after reading the  
2 deposition of Dr. Peisl where he disagreed with you in  
3 certain parts, did you do any further work based on it?

4 A. I did not.

5 JUDGE McGUIRE: See how easy that was?

6 THE WITNESS: Saved all of us a half an hour.

7 BY MR. DAVIS:

8 Q. Now, regarding the possibility of reduced good  
9 die yield due to speed distribution for --

10 A. Yes.

11 Q. -- for using fixed CAS latency, you said that  
12 you thought that there would be some die yield loss for  
13 a DRAM manufacturer who made a DRAM with fixed CAS  
14 latency of two. Is that right?

15 A. With any fixed CAS latency.

16 Q. If he fixed -- if the DRAM manufacturer fixed  
17 the CAS latency at the highest CAS latency available,  
18 would there be that -- would there have been that good  
19 die yield loss?

20 A. No, at that point, there would not have.

21 Q. Did you make an assumption of what CAS latency  
22 the DRAM manufacturer would be fixing at to arrive at  
23 your cost for good die yield?

24 A. Yes, I used the JEDEC spec CAS latencies for  
25 the SDRAM and the DDR RAM.



1           Q. I think I'm a little confused. With respect to  
2 fixed CAS latency, you say that there is going to be  
3 three parts manufactured. That's part of your  
4 assumption?

5           A. Yes, I -- my prior answer is confusing indeed.  
6 I looked at what the impact would be on the DDR RAM,  
7 but for table one, I only looked at the SDRAM and  
8 calculated the costs only for the SDRAM.

9           Q. Well, actually, what I was confused about was  
10 something a little different. You said that there's --  
11 for fixed CAS latency, you thought that they'd be  
12 making three parts.

13          A. The JEDEC spec calls out three parts.

14          Q. Three parts. Now, for the good die yield, you  
15 thought the good die yield would be reduced through  
16 speed distribution, even though they were making all  
17 three parts. Is that right?

18          A. That's correct.

19          Q. Could you explain to me how there would be a  
20 reduction in good die yield if they're already making  
21 all three parts that they would have been making  
22 anyway?

23          A. Very simple. You create a distribution of  
24 access times. If you have a programmable CAS latency,  
25 the entire distribution can become a product, in other

1 words, does not get rejected for speed. If you make  
2 CAS latency of three, you may use the entire  
3 distribution. If you make a CAS latency of three and  
4 two, you may not use the entire distribution, because  
5 two will have speed fall-out.

6 Q. So, the good die yield is based on your  
7 assumption that the JEDEC standard would be using all  
8 three -- I'm sorry, that the alternative would involve  
9 all three fixed latencies that are set out in the JEDEC  
10 standard?

11 A. That's generally -- yes.

12 Q. You also thought that a DRAM manufacturer  
13 wouldn't manufacture only a CAS latency three part,  
14 even though it might eliminate good die yield  
15 reductions, because of all of the extra money that you  
16 thought the manufacturer would get from selling the  
17 part with a CAS latency of two, for example, rather  
18 than three?

19 A. You're characterizing I believe my testimony  
20 accurately.

21 Q. Okay. And that's because the part with a CAS  
22 latency of two is faster than a part with a CAS latency  
23 of three?

24 A. It has greater value to the end customer, and  
25 the end customer pays more money for it.

1 Q. Did you do anything to determine how much of a  
2 performance gain there would have been for a CAS  
3 latency two device over a CAS latency three device?

4 A. I estimated the cost differences, and depending  
5 on where you are in the manufacturing cycle, early on,  
6 those differences are huge, because it's very difficult  
7 to make the faster parts, and later on in the cycle, it  
8 becomes less.

9 Q. But I think I asked a different question. Did  
10 you do anything to determine how much of a performance  
11 gain there would have been for a CAS latency two device  
12 over a CAS latency three device in any application?

13 A. Performance gain? No, I did not do performance  
14 evaluations at systems level.

15 Q. Did you do anything to determine how much more  
16 consumers would be willing to pay for a CAS latency two  
17 device over a CAS latency three device?

18 A. I am roughly familiar with what -- with the  
19 premiums that can be achieved there.

20 Q. You are roughly familiar. You didn't do  
21 anything to determine what that premium would be,  
22 though?

23 A. I did not specifically identify a given  
24 manufacturer, a given part and a given time period.

25 Q. Now, I'd like to talk about final test and good



1 existing fuse technology as that fuse technology.

2 Q. So, would your answer be yes to that question?

3 Let me ask the question again. That's not a --  
4 it -- you know it's a yes, but it's not good for the  
5 record.

6 You assume that the fuses would have to be  
7 burned prior to packaging. Is that right?

8 A. That is correct.

9 Q. Now, you have reviewed no evidence related to  
10 the cost to DRAM manufacturers for this element for the  
11 relevant period, did you, other than the Peisl  
12 deposition?

13 A. I was aware of the equipment and staffing  
14 requirements that were in place at final test at one of  
15 the major manufacturers, one of the first-tier  
16 manufacturers during this time period.

17 Q. And this is another set of costs that were  
18 confidential?

19 A. That's correct.

20 Q. And I couldn't have found out about those costs  
21 from you at the deposition?

22 A. That's correct.

23 Q. Now, I want to talk about inventory costs. You  
24 based your inventory cost estimate on your assumption  
25 that the number of new part numbers -- of the number of

1 new part numbers that would be required for a fixed CAS  
2 latency and a fixed burst length from the JEDEC  
3 standard. Is that right?

4 A. That's correct.

5 Q. And after multiplying it all out, you  
6 determined that you thought there would be 12 based --  
7 12 different parts for SDRAM and 15 different parts for  
8 DDR SDRAM based on what's in the JEDEC standards?

9 A. My model for CAS latency only assumed three --  
10 let me make sure I get this right. I assumed only  
11 three part numbers, and my model for burst length  
12 assumed four part numbers, as the JEDEC spec includes.  
13 I did not go to the next extreme, which is the logical  
14 extreme of combining or, if you will, multiplying those  
15 numbers to a point where, of course, it would be  
16 absurd.

17 Q. So, you did testify this morning that if you  
18 did multiply them, there would be 12 and that the cost  
19 would be much higher.

20 A. Exactly.

21 Q. Now, you never looked at the market today to  
22 see how many of those different types of parts are  
23 sold, are you -- did you?

24 A. I did not look in detail at the market today.

25 Q. And you never saw any evidence from JEDEC

1 regarding how many different types of DRAMs would have  
2 been sold had there been a fixed CAS latency and a  
3 fixed burst length?

4 A. I did not receive any information from JEDEC.

5 Q. And you never read any testimony, either from  
6 deposition or at trial, from a current industry  
7 participant regarding how many different types of DRAMs  
8 would have been sold had there been a fixed CAS latency  
9 and a fixed burst length?

10 A. I don't recall any specific testimony.

11 Q. Now, would you have considered it relevant to  
12 your opinion if it turned out that only two CAS latency  
13 values and two burst length values are used today?

14 A. If the spec were only two and two, that would  
15 be relevant. If the spec is three and four and the  
16 usage is different, that would be less relevant,  
17 because you'd still have to support all of the part  
18 numbers.

19 Q. So, just so I have an understanding of the  
20 answer to my question, you would not have considered it  
21 relevant if it turned out that there are only two CAS  
22 latency values and two burst length values used  
23 generally today?

24 MR. DETRE: I think that's the same question,  
25 Your Honor, and it's been asked and answered.





1 is in the -- in the spec.

2 Q. Well, then, my question is, would you have  
3 considered it relevant?

4 A. Of course, if the spec would have been reduced  
5 to two CAS latencies, it would have affected the  
6 inventory, increased inventory costs.

7 Q. And if the testimony were that it would be just  
8 a single CAS latency or single burst length, would that  
9 have been relevant to your costs?

10 A. If the spec was a single CAS latency and a  
11 single burst length, it would have reduced the costs.

12 Q. I'll take that as a yes.

13 I want to talk about board complexity. Now,  
14 this element is a little different from the other  
15 elements that you described today, isn't it?

16 A. That is correct. It's -- it is not in the area  
17 of DRAM component manufacturing. It's in the area of  
18 DRAM usage.

19 Q. It's also different in that you weren't able to  
20 come up with a cost number based solely on your own  
21 experience.

22 A. The experience I relied on was my experience as  
23 reliability and quality director responsible for a  
24 number of manufacturing -- manufacturing plants at  
25 Intel while --

1 Q. But you were -- I'm sorry, I didn't mean to cut  
2 you off.

3 But you needed to go to various web pages to  
4 determine which product you thought was going to be  
5 necessary to implement the alternative in order to come  
6 up with a number for board complexity. Is that right?

7 A. I needed to -- to develop cost estimates, for  
8 instance, for clock circuitry and for multiplexer  
9 circuitry to complete the model.

10 Q. And to develop those cost estimates, you went  
11 to the web pages of various companies to figure out  
12 which parts would fit in?

13 A. Yes, and -- yes.

14 Q. And then you had to determine what the price  
15 would be for that component?

16 A. I tried to establish high-volume pricing if at  
17 all possible.

18 Q. But this is one basis for your opinions that  
19 you didn't state in your report, isn't it?

20 A. I don't understand.

21 Q. You didn't state the basis for this -- the  
22 opinions regarding the cost of these components in your  
23 report?

24 A. I don't believe I specifically stated that I  
25 used web pages.

1           Q.  You didn't state that you went to the web  
2  pages?

3           A.  I -- I believe you read my report correctly.  I

1 of the components that you estimated for --

2 A. I do not recall those --

3 Q. You have got to let me finish my question, Mr.  
4 Geilhufe.

5 You don't remember the part numbers for any of  
6 the components that you put in for the board complexity  
7 aspect of your -- of your opinions?

8 A. I -- not off the top of my head. Part numbers  
9 are six, seven, eight digit long things, and I do not  
10 recall that.

11 Q. And you had those part numbers in your notes,  
12 didn't you?

13 A. Somewhere, yes.

14 Q. But you didn't bring your notes with you to the  
15 deposition, did you?

16 A. No.

17 Q. So, you couldn't tell me from your notes what  
18 the part numbers were?

19 A. No.

20 Q. You also didn't recall for sure which companies  
21 made the products that you were -- that you were using,  
22 did you?

23 A. When?

24 Q. At the deposition.

25 A. Oh, at the deposition? I believe I specified

1 one or two companies, and others I didn't recall.

2 Q. You thought that Arrow might have been one of  
3 the companies you contacted as a distributor?

4 A. That is correct.

5 Q. But you didn't remember who you spoke to at any  
6 of the companies?

7 A. No.

8 Q. Now, in your direct, you didn't mention the  
9 part numbers that you got the prices for, did you?

10 A. No, I did not.

11 Q. Have you -- and you don't recall what the price  
12 numbers -- I'm sorry, what the part numbers are sitting  
13 here today?

14 A. No, I do not.

15 Q. Did you bring your notes with you today so that  
16 you could tell me what part numbers you got the prices  
17 for?

18 A. I do not -- I did not.

19 Q. So, if I wanted to check on whether the part  
20 numbers that you identified were the appropriate part  
21 numbers to solve the problems that you identified or  
22 that Dr. Jacob identified, I wouldn't be able to do  
23 that from the information you provided me, would I?

24 A. I -- since I did not provide --

25 JUDGE McGUIRE: I think he's answered that now

1 about five times, Mr. Davis. Let's get off the part  
2 numbers.

3 MR. DAVIS: Okay.

4 BY MR. DAVIS:

5 Q. In your analysis of Professor Jacob's double  
6 clock frequency alternative for dual edge clocking, you  
7 testified that you thought that an on-DIMM clock would  
8 be required to adequately -- I'm sorry, accurately  
9 position the clock. Isn't that right?

10 A. That is correct.

11 Q. And you were referring to an on-DIMM PLL or  
12 DLL?

13 A. On-DIMM PLL or DLL clock circuit, maybe more  
14 than a PLL/DLL.

15 Q. You didn't do any timing analysis to ensure  
16 that you were correct in your assertion that an on-DIMM  
17 clock or an on-DIMM DLL would be required, did you?

18 A. I made hopefully the good technical assumption  
19 if we're removing a DLL from the chip, and we certainly  
20 would need some -- a DLL on the DIMM, but I did not  
21 make the timing -- detailed timing analysis.

22 Q. And just so we're clear, for this alternative,  
23 I was -- I wasn't talking about removing the DLL. I  
24 was talking about doubling the clock frequency.

25 A. I apologize for the wrong answer.

1 Q. But that doesn't change your answer, does it?

2 A. No, it doesn't.

3 Q. Now, in coming up with your cost for the clock  
4 PLL or PLL or DLL, you didn't look to see what the cost  
5 of similar components were for either register DIMMs or  
6 for the Kentron's QBM DIMMs?

7 A. I made an attempt to identify the cost for the  
8 Kentron DIMMs, and interestingly enough, the high-speed  
9 DIMMs are not available, and information about them was  
10 only available via nondisclosure agreement, which  
11 suggests that the product is not yet commercially  
12 available.

13 Q. The cost for the PLL is not -- I was talking  
14 about the cost for the PLL, and that's not available  
15 you're saying?

16 A. The Kentron solution. You asked specifically  
17 about the Kentron solution, and that's the answer I'm  
18 giving.

19 MR. DAVIS: Can I have one second, Your Honor?

20 JUDGE McGUIRE: All right.

21 (Counsel conferring.)

22 BY MR. DAVIS:

23 Q. I'd like to show you what's been marked for  
24 identification as CX-2613.

25 May I approach, Your Honor?





1 A. May I put my glasses on?

2 Q. You can look at the screen, actually. I think  
3 it's on there.

4 A. Okay. So, that's -- that puts us in September  
5 of 2002.

6 Q. Now, this is the QBM Kentron DIMM that you were  
7 referring to earlier in your answer just a minute ago.

8 A. That is -- that is correct.

9 Q. Now, could you turn to page 7 of the exhibit,  
10 and the top slide there, do you see a table?

11 A. Yes.

12 Q. Refer to the first column, which says QBM533.

13 A. Correct.

14 Q. And focus on the third row from the bottom. Do  
15 you see it says, "PLL," and the cost is \$2?

16 A. Right.

17 Q. Did you see this document prior to putting  
18 together your opinion in this case?

19 A. I believe I saw this document, yes.

20 Q. Okay. And you didn't include this as a -- did  
21 you consider this as part of the cost of PLL?

22 A. Of course. I actually tried to establish what  
23 the PLL cost at Kentron is, and the response was I  
24 needed to sign a nondisclosure agreement to get that --  
25 access to that information.

1 Q. So, it wasn't good enough to see the \$2 in the  
2 presentation; you wanted to get what they considered  
3 confidential information on what the PLL cost was?

4 A. Mr. Davis, I have generated hundreds of  
5 marketing presentations, and I've seen thousands, and  
6 just because a number is on a slide does not mean it is  
7 either available or it's -- actually a transaction has  
8 taken place at that price.

9 Q. So, you didn't believe that \$2 price?

10 A. I have no judgment. I could not confirm it.

11 Q. And did you consider the cost for PLLs for  
12 registry DIMMs?

13 A. I did not review specifically the costs for  
14 register DIMMs.

15 Q. Now, with your -- I'm sorry, with your cost  
16 estimate for the clock/PLL that we were talking about,  
17 the -- you think the double clock frequency alternative  
18 would cost about 28 cents more than the dual edge  
19 clocking alternative?

20 A. That is correct, that's what I projected in my  
21 model.

22 Q. And 24 cents of that 28 cents comes from that  
23 PLL?

24 A. Approximately 24 cents.

25 Q. Now, I'd like to talk about a few of the actual

1 technology alternatives themselves.

2 Now, let's look at some of the -- some of your  
3 overall conclusions regarding the costs of some of  
4 these alternatives. You think that a fixed CAS latency  
5 and fixed burst length would increase costs by 6 cents  
6 and 4 cents, respectively, over the JEDEC standard, the  
7 current JEDEC standard technology?

8 A. That is correct. That's what I've shown on the  
9 table.

10 Q. Now, you'll recall earlier we talked about  
11 SDRAM-Lite a little bit?

12 A. I don't believe SDRAM-Lite -- yes, you asked  
13 questions about it.

14 Q. Did you know that in 19 -- that there's  
15 testimony to the effect that in 1995, fixed CAS latency  
16 and fixed burst length parts were being proposed as  
17 part of the SDRAM-Lite standard to lower costs relative  
18 to the current standard?

19 A. I'm not aware of that, and of course, SD-Lite  
20 is not a significant DRAM product, so history or the  
21 actual marketplace has decided that that's -- was  
22 probably incorrect.

23 Q. You didn't review the SDRAM-Lite proposals?

24 A. I did not.

25 Q. And you didn't talk to anybody who was at JEDEC

1 who reviewed those proposals?

2 A. I did not talk to anyone at JEDEC. You don't  
3 need to ask that question again.

4 Q. Now, let's talk about voltage levels via pin to  
5 set CAS latency and burst length. Is it accurate for  
6 me to say that virtually all of the costs for this  
7 alternative are based on your assumption that  
8 additional pins would be needed to implement this  
9 alternative?

10 A. My analysis and testimony did not address  
11 voltage levels of the pins.

12 Q. I see what you're saying. You're looking at  
13 voltage level, multiple voltage levels.

14 A. That is correct, yes.

15 Q. I'm referring to the analysis that you did of  
16 burst length via pins and CAS latency via pins.

17 A. Okay, that has nothing to do with voltage  
18 levels, just the pin.

19 Q. Two voltage levels, right?

20 A. Right.

21 Q. It's fair to say that virtually all of the  
22 costs -- in fact, all of the costs for this alternative  
23 are based on the assumption that additional pins would  
24 be required to implement this alternative. Is that  
25 right?

1 A. That is correct.

2 Q. And you base that assumption that more pins  
3 would be required on your reading of Professor Jacob's  
4 report?

5 A. Professor -- Professor Jacob suggested using  
6 additional pins, and I identified how many pins would  
7 be required to support the three bits for CAS latency  
8 and three bits for burst length.

9 Q. But you didn't do anything to ensure that it  
10 was the case that you actually did need more pins to --  
11 to use this alternative, did you?

12 A. Professor Jacob did not suggest any other --  
13 excuse me. No, I did not.

14 JUDGE MCGUIRE: Thank you.

15 BY MR. DAVIS:

16 Q. You didn't look at any JEDEC -- I'm sorry, at  
17 the JEDEC standard to see if there were standard  
18 packages that had no-connects that could have been  
19 used?

20 A. Of course, I did.

21 Q. And you found that there were packages that had  
22 multiple no-connect pins when you did that, correct?

23 A. I found as part of the JEDEC standards that all  
24 the standards used either at the 44 or the 54 or the 66  
25 pin level, they used up all the pins in the highest

1 density cases. So, the standard used up all the pins  
2 in the highest density cases.

3 Q. Well, I'm not sure I understand that answer.  
4 Let's look at CX-234, which is the JEDEC standard, you  
5 should have it in front of you still, and I'm talking  
6 about page 83.

7 A. What's the page number?

8 Q. Page 83.

9 A. Um-hum.

10 Q. And this is a -- are you at that point, page  
11 83?

12 A. I'm on page 83.

13 Q. And this is a schematic or a drawing of the  
14 pin-out for the 16, 32 and 64-meg x4 SDRAM in TSOP-2.  
15 Is that right?

16 A. That's correct.

17 Q. And if you look at that picture, there are open  
18 or no-connect pins at 17, 25, 43 and 53. Is that  
19 right?

20 A. That's correct.

21 Q. So, there are four open pins; there are four  
22 no-connect pins in this particular pin-out.

23 A. On this particular version.

24 Q. So, there would be 16 options, is that right,  
25 16 options for CAS latency and burst length using this

1 particular -- this particular pin-out?

2 A. Only for this configuration of DRAM. The  
3 standard provides for all configurations of DRAM, and  
4 other configurations, of course, don't have any -- have  
5 four -- do not have four pins available.

6 Q. Could you turn to page 80?

7 A. Eighty, yes.

8 Q. And this is a two-meg x4.

9 A. Yes, much smaller SDRAM.

10 Q. And this is an SDRAM rather than a DDR SDRAM,  
11 right?

12 A. That's correct.

13 Q. And there are open pins for or no-connect pins  
14 on 30 and 34 there, correct?

15 A. Correct.

16 Q. So, that's four options, not as many as the  
17 first time, but --

18 A. Right, but again, the SDRAM spec does not  
19 confine itself to a 16-meg x4. It covers the range of  
20 densities, so we have to look at the worst case  
21 packaging situation.

22 Q. But this SDRAM spec was put together along with  
23 the assumption that there would be a mode register.  
24 Isn't that right?

25 A. Correct.

1 Q. Now, with respect to your table -- you can take  
2 that off -- with respect to your tables describing  
3 fixed costs, those are one-time costs. Is that right?

4 A. That's correct, one-time costs per product  
5 type.

6 Q. Per product type?

7 A. Per product part number, if you will.

8 Q. So, you'd only -- for example, for the design,  
9 you would spend the money for the design, and then  
10 you'd have the design.

11 A. That -- that is the model there.

12 Q. You wouldn't be spending another \$250,000 or  
13 \$100,000 next year to do the same design; you've  
14 already got that. Is that right?

15 A. That is why this es pr ght? pr castsnservatin; you've

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1 that right?

2 A. That's correct.

3 Q. Is it 20 million units of output of DRAM, is  
4 that what you were referring to?

5 A. 20 million DRAMs.

6 Q. Is that 20 million DRAMs per year?

7 A. That's 20 million DRAMs for that particular  
8 iteration.

9 Q. 20 million -- oh, that's what I didn't  
10 understand. So, it's 20 million DRAMs for the entire  
11 iteration; for the life of that product, there would be  
12 20 million DRAM.

13 A. For that iteration; that is, if you did a  
14 shrink, it would be a separate iteration.

15 Q. But I thought that this was a -- based on a  
16 mature product, that there weren't going to be any more  
17 shrinks after --

18 A. It's possible that there are further shrinks,  
19 but I -- I assumed that 20 million units could be built  
20 off that one design effort.

21 Q. So, there could be further shrinks off of the  
22 design that you talked about?

23 A. Potentially.

24 Q. Okay. Going back to the double clock frequency  
25 for a second?

1 A. Yes.

2 Q. If you want to take a sip of coffee, go ahead.

3 A. I appreciate it.

4 Q. You said that you thought a DLL or PLL type  
5 chip would be required on the module to distribute the  
6 clock. That's why you added that component to the  
7 DIMM.

8 A. That is -- that is correct.

9 Q. What clock frequencies were you assuming would  
10 be used?

11 A. 200 megahertz.

12 Q. 200 megahertz. Did you look at the DDR 400  
13 modules currently on the market to see if they used  
14 PLLs or clock chips or DLL-type chips on the module?

15 A. I think I already testified that I did not look  
16 at the register modules.

17 Q. Well, no, I'm not talking about the register  
18 modules. I'm talking about the unbuffered,  
19 unregistered modules, DDR 400. Did you look at those  
20 modules?

21 A. I did not -- I looked at a whole series of  
22 Samsung -- I may have looked at them. I don't recall.

23 Q. Those modules, the clock speed for those  
24 modules is 200 megahertz, right?

25 A. Right, but doubling the 200 megahertz goes to

1 400 megahertz. We're now operating at twice that  
2 speed.

3 Q. Right. So, it's -- the clock speed for that  
4 module is 200 megahertz?

5 A. The -- let's be very precise. We're doubling  
6 clock speed here. 200 megahertz clock speeds, it now  
7 needs to operate at 400 megahertz, and I believe that  
8 requires an on-DIMM clock generator.

9 Q. So, you were assuming a 400-megahertz clock  
10 when you put together this table or a 200-megahertz  
11 clock when you were putting together this table?

12 A. The dual edge clock alternative operating at  
13 200 megahertz requires a 400-megahertz clock in this  
14 alternative.

15 Q. Yeah, I'm just asking what you assumed when you  
16 were putting together your table. Were you assuming  
17 the clock would be going at 200 megahertz or were you  
18 assuming it would be going at 100 megahertz or were you  
19 assuming that it would go at 400 megahertz? I just  
20 want to know how fast the clock was going.

21 A. Okay, the actual clock was going at 400  
22 megahertz, and I looked at a range.

23 Q. 400 megahertz for the clock alternative?

24 A. Yeah.

25 Q. Now, did you know that Mark Kellogg of IBM

1 testified that they expect to be able to run a clock at  
2 two and a half gigahertz in the near future?

3 A. I -- I read all kinds of good things in the  
4 literature and people tell me all kinds of good things.  
5 I wouldn't be surprised if somebody said that today.  
6 This is 2003.

7 Q. Did you talk to Mark Kellogg or anyone else  
8 about whether PLL would be required on the DIMM in  
9 order to implement that?

10 A. In the 1999 time frame, I did not.

11 Q. In any time frame?

12 A. I did not.

13 Q. Now, one of the things you mentioned early  
14 today when I first started asking you questions was  
15 that you had read some documents -- you recalled  
16 reading some documents and you might have read some  
17 testimony, but you weren't able to recall who. Do you  
18 remember that testimony?

19 A. That's correct.

20 Q. I just want to give you some names and ask you  
21 if you recall reading testimony of these people.

22 Do you remember reading the testimony of Desi  
23 Rhoden?

24 A. I may have seen it, a piece of it or -- I  
25 don't -- I certainly don't remember reading the whole

1 thing.

2 Q. Do you recall reading any of it?

3 A. How do you spell the last name?

4 Q. R H O D E N.

5 A. I believe -- I may have seen a piece of it.

6 Q. You don't have any specific recollection of the  
7 piece, but you think you might have read it?

8 A. No, I do not.

9 Q. I understand. Do you recall reading any  
10 testimony of Howard Sussman?

11 A. I don't recall.

12 Q. Do you recall reading any testimony from Mark  
13 Kellogg?

14 A. I may have seen some piece of testimony of his.

15 Q. Okay, but you don't recall specifically?

16 A. I don't recall specifics, no.

17 Q. Did you read the testimony of Terry Lee?

18 A. I don't recall.

19 Q. Did you read the testimony of Joe Macri?

20 A. I don't recall.

21 Q. And did you read the testimony of Andy  
22 Bechtolshein?

23 A. I did not. That one I didn't.

24 Q. You would have remembered his name?

25 A. I'd remember that.

1 Q. Did you read the testimony of Kevin Ryan?

2 A. I did not.

3 JUDGE McGUIRE: All right, it would be a lot  
4 easier if we just asked him what he did read.

5 MR. DAVIS: I asked him, and he didn't  
6 remember.

7 JUDGE McGUIRE: Okay, then he's answered it.

8 MR. DAVIS: Actually, I just finished the last  
9 one.

10 JUDGE McGUIRE: Lucky for you.

11 BY MR. DAVIS:

12 Q. Now, each of the alternatives to dual edge  
13 clocking that Dr. Jacob proposed --

14 A. Yes.

15 Q. -- none of those alternatives would end up  
16 using both edges of a clock, right, that you evaluated?  
17 So, you might want to just look at that --

18 A. Oh, I would totally disagree with that. You  
19 can't utilize two banks without using both edges of the  
20 clock.

21 Q. Okay. So, other than that first alternative,  
22 the on-chip memory banks, the remaining alternatives  
23 didn't use both edges of the clock. Is that accurate?

24 A. In one form or another. The precise timing of  
25 bringing data out, with the exception of doubling the

1 data with going around, it would require bringing data  
2 out on the two edges of the clock.

3 Q. Okay.

4 I may be very nearly done, Your Honor.

5 Now, the last alternative that I think I want  
6 to talk about, and I want to make sure that it's the  
7 last one, but I believe it is, is -- is the programming  
8 the values for CAS latency and burst length of fuses,  
9 one we were talking about this morning.

10 A. Okay.

11 Q. Now, with respect to the alternative of  
12 programming CAS latency in fuses, you assume that the  
13 alternative involved was to use laser-blown fuses to  
14 set the --

15 A. That's correct, because that's existing  
16 technology at that time.

17 Q. And you didn't think any other type of fuse  
18 technology was feasible for DRAMs?

19 A. At -- at the time frame of 1995, I believed --  
20 yes, I did not believe there was any other technology  
21 that was feasible.

22 Q. In fact, you thought that anti-fuse technology  
23 wasn't even feasible today. Isn't that accurate?

24 A. Anti-fuse technology is less reliable than  
25 laser-blown fuse technology, and it carries with it a

1 risk.

2 Q. So, you thought that anti-fuse technology has a  
3 reliability factor which is inconsistent with the cost  
4 objectives with something as complicated and expensive  
5 as DRAM manufacture. Is that right?

6 A. Yes, that is my belief.

7 Q. And you also thought that the need for an  
8 additional application module also meant that DRAM  
9 manufacturers wouldn't use the technology on DRAMs,  
10 correct?

11 A. If the anti-fuse technology module is not  
12 available in the DRAM process, then I would think a  
13 manufacturer would resist or not implement it, because  
14 it would add cost.

15 Q. You don't think they would add the module, in  
16 other words.

17 A. Just for fusing, because the DRAM manufacturers  
18 already have laser-blown fuse technology in place.  
19 Unless there is a compelling cost or reliability or  
20 performance improvement, one wouldn't implement it.

21 Q. You didn't review any evidence in this case  
22 regarding whether DRAM manufacturers actually used  
23 anti-fuses to set -- to do their redundancy work that  
24 you were referring to?

25 A. I became aware of testimony on Friday that



1 Micron currently is using some anti-fuse technology.

2 Q. And this was something that you didn't know  
3 when you were -- when you were writing your opinion?

4 A. No, I was aware that Micron was using anti-fuse  
5 technology for some parts, but not in the 1995 time  
6 frame.

7 Q. Did you know when they were using it?

8 A. I estimated it to be somewhere in the '98,  
9 '97-'98 time frame.

10 Q. Okay, but you said in your deposition that you  
11 thought that anti-fuses were -- first of all, that  
12 you -- you said that they had a reliability factor  
13 which is inconsistent with the cost objectives of  
14 something as complicated and expensive as DRAM  
15 manufacturer, in your deposition you said that, right?

16 A. Right.

17 Q. But you knew at the time you said that that  
18 Micron was actually using fuses for that purpose?

19 A. Oh, and it is still my belief that that may,  
20 indeed, be a special skill either that Micron has or a  
21 special yield loss that Micron deals with.

22 MR. DAVIS: Your Honor, could I take a  
23 five-minute break to make sure? I think I may be done.

24 JUDGE McGUIRE: Okay, good enough. Three  
25 minutes.

1 (Pause in the proceedings.)

2 JUDGE McGUIRE: Mr. Davis, any further cross?

3 MR. DAVIS: No more questions.

4 JUDGE McGUIRE: All right, thank you very much.

5 Did you want to follow up, Mr. Detre, redirect?

6 MR. DETRE: Yes, Your Honor, just a few  
7 questions.

8 JUDGE McGUIRE: Okay.

9 REDIRECT EXAMINATION

10 BY MR. DETRE:

11 Q. Mr. Geilhufe, do you recall Mr. Davis asked you  
12 about the margin of error in connection with some of  
13 your estimates?

14 A. Yes, I do.

15 Q. Now, when you were making your estimates in  
16 this case, were you trying to be -- were you trying to  
17 err on one side or the other?

18 A. I -- I attempted to be as realistic as possible  
19 but err on the serve of conservatism.

20 Q. Okay. Is that the practice you generally  
21 followed when you were making these estimates in the  
22 industry?

23 A. Clearly those of us who have to take  
24 responsibility for building stuff that we project have  
25 to be fairly conservative in our estimates.

1 Q. Some of your cost estimates involved estimating  
2 the costs of a pin in the 1995 time frame, correct?

3 A. That is correct.

4 Q. What -- and you estimated that at about a penny  
5 a pin. Is that right?

6 A. That is correct.

7 Q. What would you say the margin of error is with  
8 respect to those pin estimates specifically?

9 A. Those were quite accurate since those were  
10 industry standard numbers at that time period, so  
11 certainly within 10 percent.

12 Q. Now, Mr. Davis asked you some questions about  
13 whether you could, in connection with some of your  
14 alternatives, remove circuitry from a DRAM. Do you  
15 recall those questions?

16 A. Yes.

17 Q. And you testified you took that into account?

18 A. Yes, I did.

19 Q. Now, specifically, or let's go to fixed CAS  
20 latency, if we went to fixed CAS latency, could you  
21 remove all or --

22 A. One second.

23 Q. I'll let you get there.

24 With respect to fixed CAS latency, could you  
25 remove all or any part of the mode register if you

1 employed that alternative?

2 A. Of course not. The mode register serves a  
3 series of purposes, not only CAS latency. It serves  
4 the purpose of CAS latency, burst length, burst type,  
5 test mode. In the SDRAM, it's a 22-bit long register.

6 Q. Now -- so, you couldn't remove the whole thing,  
7 but could you remove the bits that are specific to CAS  
8 latency?

9 A. Indeed, you certainly could remove -- if you go  
10 to a fixed CAS latency, you could take the 22-pin --  
11 bit register and lower it to 19 bits.

12 Q. What --

13 A. Which --

14 Q. -- what would the cost savings be in removing  
15 three bits from the mode register?

16 A. Totally negligible. It would probably include  
17 removal of 36 to 40 transistors on a chip that has 10  
18 million transistors. It's a completely negligible  
19 effect.

20 Q. Now, you mentioned that it was a requirement  
21 that every DRAM be able to output a single data bit.  
22 Do you recall that testimony?

23 A. That's correct.

24 Q. Why is that?

25 A. Single word addressing is a requirement of some

1 applications. Some other applications take data  
2 streams and bursts; other applications require a great  
3 deal of random access memory. Let's recall what we're  
4 dealing with. We're dealing with a random access  
5 memory, which suggests you can get to any word  
6 independently.

7 Q. How does that apply to, say, DDR SDRAM?

8 A. In the DDR SDRAM, of course, because it clocks  
9 out two bits in a single clock cycle, it brings out two  
10 words at the same time. That's its minimum increment.

11 Q. If -- could we put up DX-298, please?

12 With respect to programming CAS latency with  
13 fuses, you testified that there would be reduced yield  
14 due to speed distribution. Do you recall that  
15 testimony?

16 A. That's correct.

1 that was what was in the JEDEC spec. Do you recall  
2 that?

3 A. That's correct.

4 Q. Did you think that it was appropriate to look  
5 at what was in the JEDEC spec as opposed to what parts  
6 are in use today?

7 A. Of course. The JEDEC spec determined the  
8 requirements that the industry and the DRAM  
9 manufacturers, the DRAM consumers, the software  
10 writers, what have you, felt was necessary to go  
11 forward. The JEDEC spec is a document that addresses  
12 several generations of product. It addresses a lengthy  
13 time period. And at that time, there was no  
14 information whatsoever as to which one of the CAS  
15 latencies would be prevalent or if only a few would be  
16 prevalent.

17 JUDGE MCGUIRE: Mr. Davis?

18 MR. DAVIS: Your Honor, move to strike  
19 everything after "of course," Mr. -- for foundation.  
20 Mr. Geilhufe stated he didn't know anything about  
21 JEDEC, didn't interview anybody about JEDEC, didn't  
22 review any documents about JEDEC.

23 JUDGE MCGUIRE: I'll let you answer, but I'm  
24 inclined to --

25 MR. DETRE: Mr. Geilhufe did say he looked at

1 the JEDEC spec. He didn't say he looked at other JEDEC  
2 documents, but he did say he looked at the JEDEC spec,  
3 and this only goes to why he used that spec in a  
4 certain way.

5 JUDGE McGUIRE: Is that your understanding of  
6 his testimony, Mr. Davis?

7 MR. DAVIS: If that is his understanding of his  
8 testimony, he can talk about what was in the spec, but  
9 that's not what his answer gave.

10 MR. DETRE: Well, what was in the spec was  
11 three latency values, and --

12 JUDGE McGUIRE: It's the question that I was  
13 looking at, not what was in the spec. I will hear it  
14 on that basis, only what was in the spec and what he  
15 had reviewed in the spec.

16 BY MR. DETRE:

17 Q. You'll recall, Mr. Geilhufe, that Mr. Davis was  
18 asking you some questions about anti-fuse technology.

19 A. That's correct.

20 Q. Do you know whether there were DRAM  
21 manufacturers in the 1995 to 2000 time frame who did  
22 not have anti-fuse technology available?

23 A. I'm aware of one major one that definitely did  
24 not, and I -- it's -- I believe several other ones did  
25 not.

1 Q. Okay. Which one are you aware of that  
2 definitely did not?

3 A. At that time, Samsung definitely did not.

4 Q. That's based on your own personal experience  
5 with Samsung?

6 A. Yes, and this is public information. This is  
7 not confidential information.

8 Q. Okay. Now, if you've got CX-234 in front of  
9 you, Mr. Geilhufe, that's the JEDEC spec, Release 9.  
10 Could you pull that up?

11 A. Yes.

12 Q. I'll just wait for it to come up on the screen,  
13 CX-234.

14 Could you turn to page 84 of that document, 84  
15 of the exhibit?

16 A. Yes.

17 Q. There are certain SDRAM configurations shown on  
18 this page. Do you see that?

19 A. Yes, I do.

20 Q. And there is in particular a -- the outer ring  
21 of this diagram shows a particular SDRAM configuration?

22 A. That is correct.

23 Q. Could you check whether there are any  
24 no-connect pins available there?

25 A. That configuration does not have any



1 no-connects.

2 MR. DETRE: No further questions.

3 JUDGE McGUIRE: Okay, Mr. Davis, any recross?

4 MR. DAVIS: Thank you, Your Honor.

5 RE CROSS EXAMINATION

6 BY MR. DAVIS:

7 Q. Mr. Geilhufe, you -- in response to questions  
8 from Mr. Detre, you talked about the practice in the  
9 industry to be conservative in estimates regarding  
10 cost. Do you remember that?

11 A. Yes.

12 Q. And that was as a customer, you were in a sense  
13 buying DRAM from people who were manufacturing it for  
14 you, where you were in control of the plants or  
15 whatever, but you were talking about the costs of those  
16 products. Is that correct?

17 A. I'll give a broader answer. I view that both  
18 as a manufacturer for cost analysis in an internal fab  
19 factory and for contract acquisition of manufacturing  
20 capacity where you're purchasing the capacity from the  
21 outside. So, it's both conservative on the high end  
22 and low side.

23 Q. Conservative on the high end, okay.

24 Now, if you -- I'd like to refer you to the  
25 mode register page on the JEDEC standard, Release 9.

1 A. What page is that, please?

2 Q. Which I believe it's on page 150 of CX-234, and  
3 that's the SDRAM and SGRAM mode register?

4 A. That's correct.

5 Q. And in fact, it also has the DDR CAS latency  
6 values there as well. Is that right?

7 A. That is correct.

8 Q. And the DDR burst length values are there as  
9 well, correct?

10 A. That is correct.

11 Q. Okay. Now, if you removed as an alternative  
12 the burst length and the CAS latency from the mode  
13 register, what would be left -- you would be left with  
14 is the BT register, I guess, which is number three  
15 there, is that right, bit number three? That's all  
16 that would be left.

17 A. Okay.

18 Q. Now, one of the things that you said in your  
19 redirect was that you had to have a burst length of  
20 one, right, that was a requirement for DRAMs?

21 A. Yes, random access.

22 Q. Could you show me where on this, on this mode  
23 register, a burst length of one is specified in the  
24 mode register?

25 A. Yes, 000.

1 Q. 000 for both SDRAM and DDR SDRAM establishes a  
2 burst length of one. Is that accurate?

3 A. It -- this only specifies it for SDR RAM.

4 Q. So, for DDR SDRAM, 000 in those bits actually  
5 is reserved?

6 A. It's reserved, yes, for something else.

7 Q. And 001 for DDR and for SDR is a burst length  
8 of two. Is that right?

9 A. That is correct.

10 Q. So, DDR doesn't even have a burst length of one  
11 specified in that -- in the mode register.

12 A. Of course, double data rate suggests you get  
13 two bits or a nibble per access.

14 Q. And if you look at the SDRAM, the SDRAM part of  
15 the mode register for burst length, do you see the one  
16 there is in parentheses?

17 A. Yes.

18 Q. Do you know what that means?

19 A. According to the -- no, I don't. I don't  
20 recall.

21 Q. Okay. If you look at the very bottom, and  
22 actually, for some reason it's covered up, at the  
23 bottom of the table, at the bottom of the bottom  
24 table -- yes, highlight that, please.

25 A. Yes, as a matter of fact, I apologize. Of

1 course, they're options.

2 Q. It's optional?

3 A. Yes. It's getting late in the afternoon, Mr.  
4 Davis.

5 MR. DAVIS: No more questions, Your Honor.

6 JUDGE MCGUIRE: Okay, very good, sir. Thank  
7 you for your testimony --

8 MR. DETRE: Your Honor, I have one follow-up  
9 question, just one.

10 JUDGE MCGUIRE: You better ask the Court, then,  
11 because I haven't gone two rounds.

12 MR. DETRE: Well, Your Honor, may I ask one  
13 follow-up question just to clarify something?

14 JUDGE MCGUIRE: Yes.

15 FURTHER REDIRECT EXAMINATION

16 BY MR. DETRE:

17 Q. Mr. Geilhufe, in response to Mr. Davis'  
18 questions, you were talking about how when you were  
19 taking cost estimates in the industry, you would be  
20 conservative on the high end and the low end. Do you  
21 recall that?

22 A. That is right.

23 Q. Now, for purposes --

24 MR. DAVIS: I'm sorry, objection, that  
25 misrepresents his testimony, I believe.

1 JUDGE McGUIRE: I can't even see what you said.

2 Then restate, Mr. Detre. See, your one  
3 question, you messed it up. So, I could ask you to sit  
4 down right now.

5 MR. DETRE: I'll try to do better, Your Honor.  
6 I'll withdraw that question, if I may, and ask a  
7 different question.

8 BY MR. DETRE:

9 Q. For purposes of this case, Mr. Geilhufe, were

1 morning we will call Mr. Richard Rapp, an economic  
2 expert. We are pretty sure it will take the whole day.

3 JUDGE McGUIRE: Okay, very good. I have got  
4 some hard copy up here. We will see you in the morning  
5 at 9:30. Hearing in recess.

6 (Whereupon, at 3:50 p.m., the hearing was  
7 adjourned.)

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1 C E R T I F I C A T I O N O F R E P O R T E R

2 DOCKET NUMBER: 9302

3 CASE TITLE: RAMBUS, INC.

4 DATE: JULY 21, 2003

5

6 I HEREBY CERTIFY that the transcript contained  
7 herein is a full and accurate transcript of the notes  
8 taken by me at the hearing on the above cause before  
9 the FEDERAL TRADE COMMISSION to the best of my  
10 knowledge and belief.

11

12 DATED: 7/22/03

13

14

15

16 SUSANNE BERGLING, RMR

17

18 C E R T I F I C A T I O N O F P R O O F R E A D E R

19

20 I HEREBY CERTIFY that I proofread the  
21 transcript for accuracy in spelling, hyphenation,  
22 punctuation and format.

23

24

25 SARA J. VANCE

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